

FIG. 1A

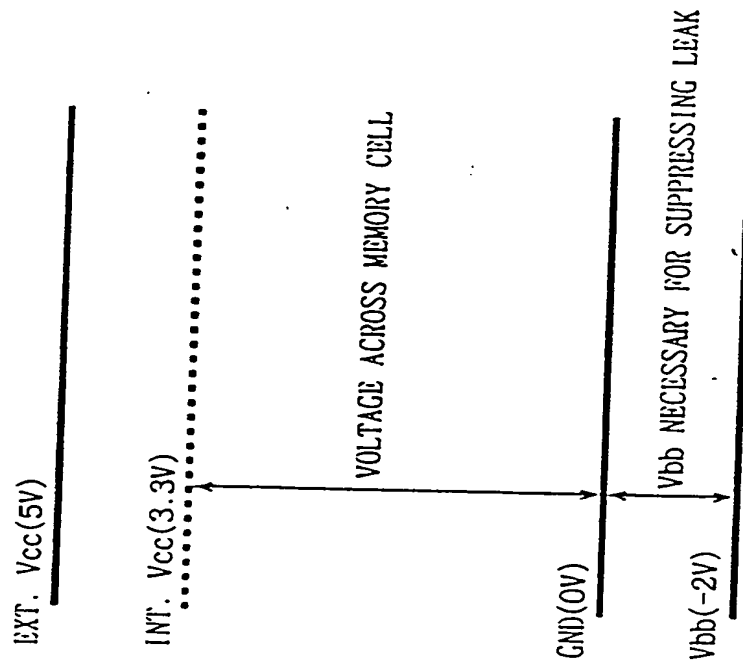


FIG. 1B

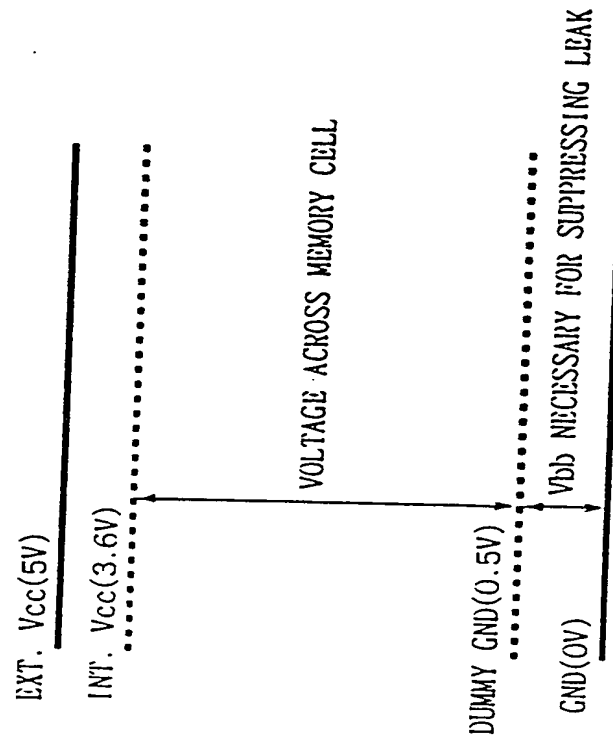


FIG. 2

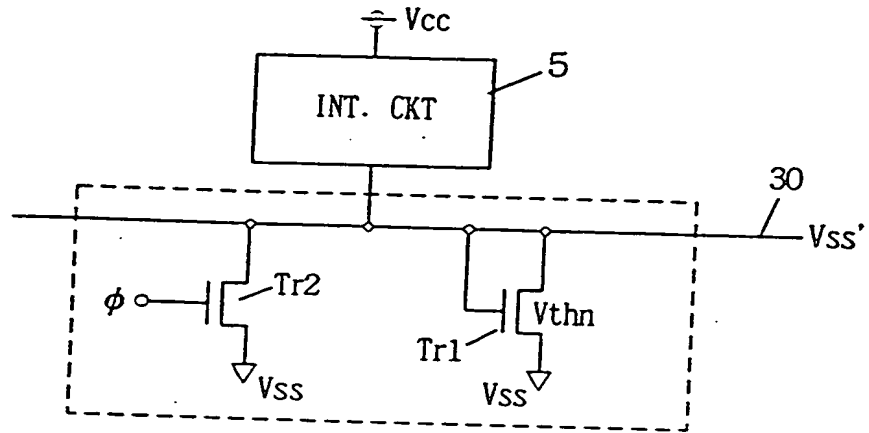


FIG. 3

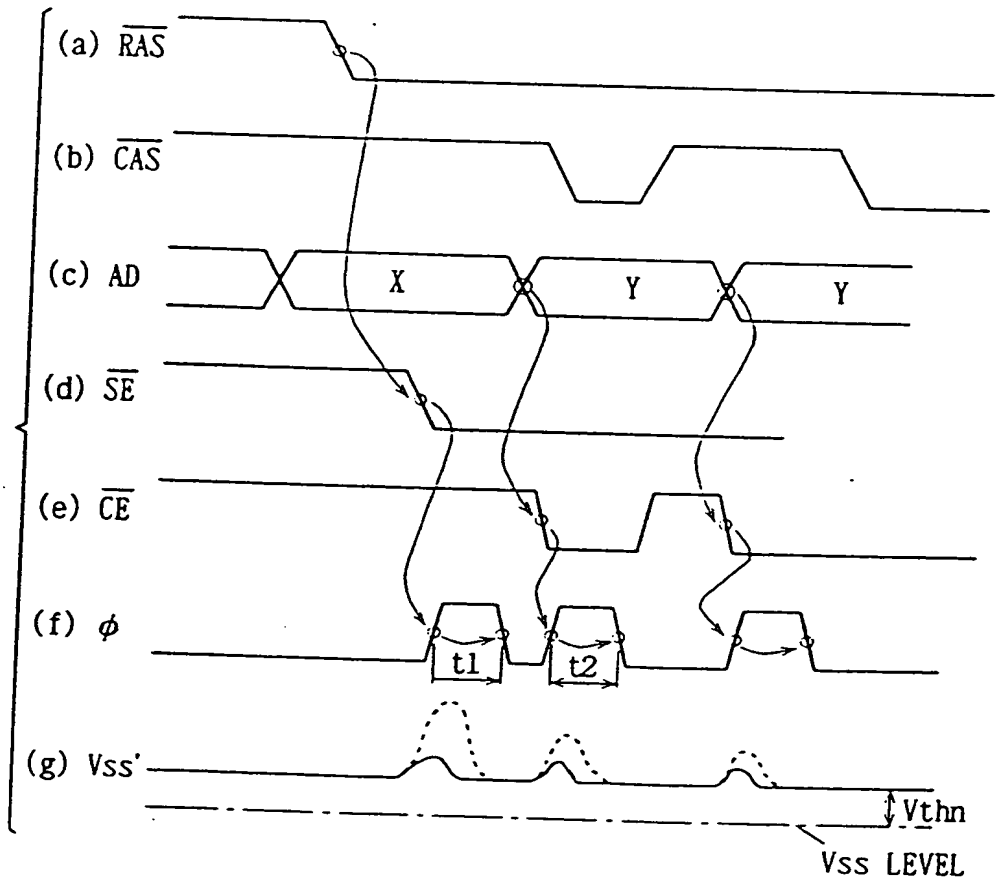


FIG. 4

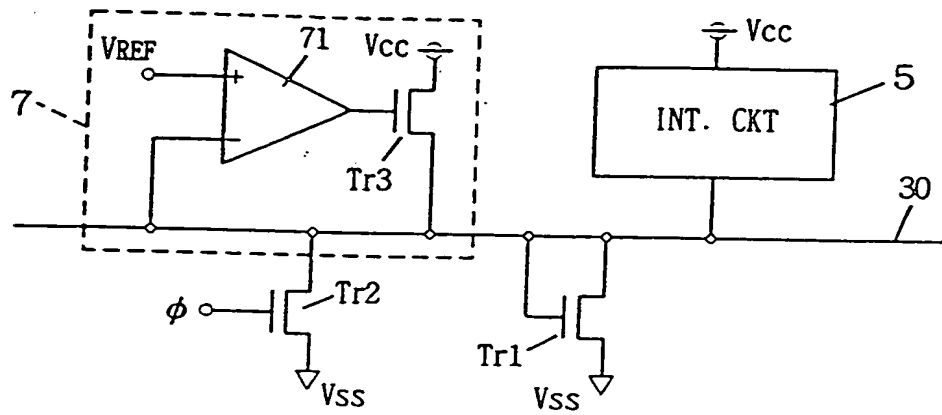


FIG. 5

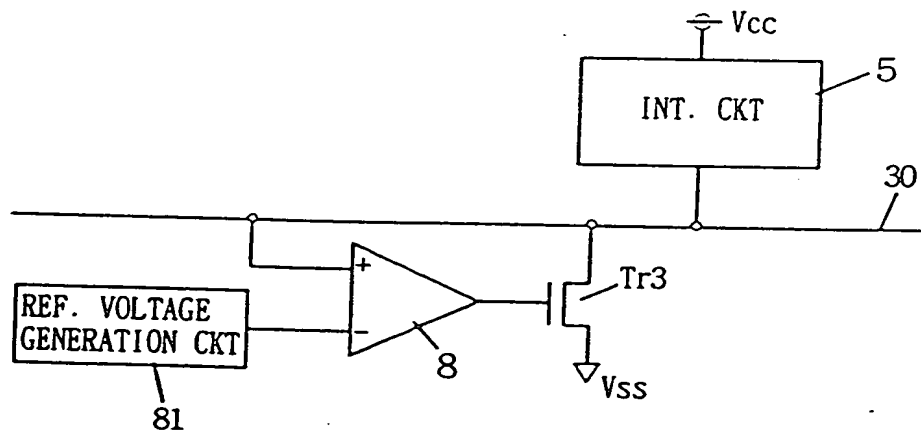


FIG. 6

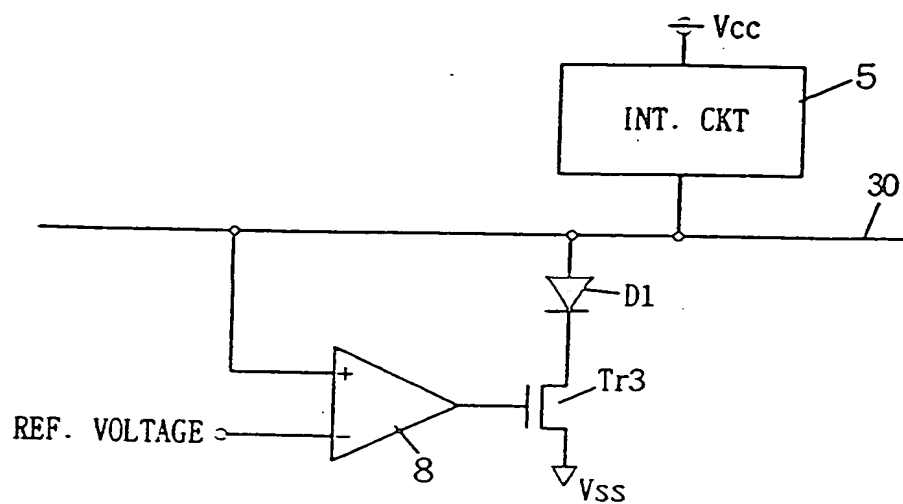


FIG. 7

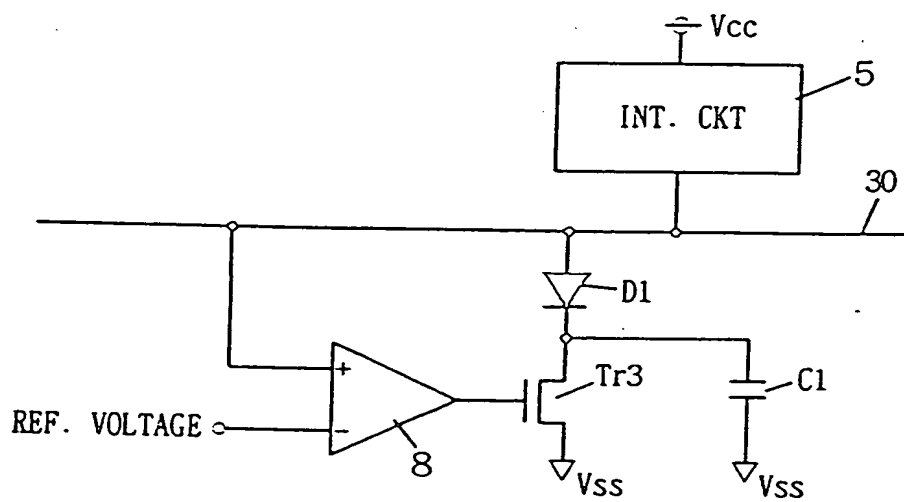


FIG. 8

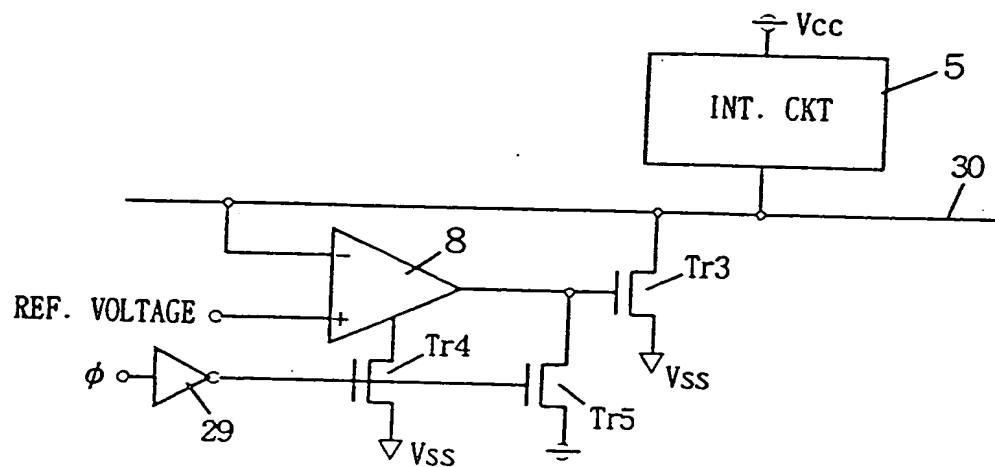
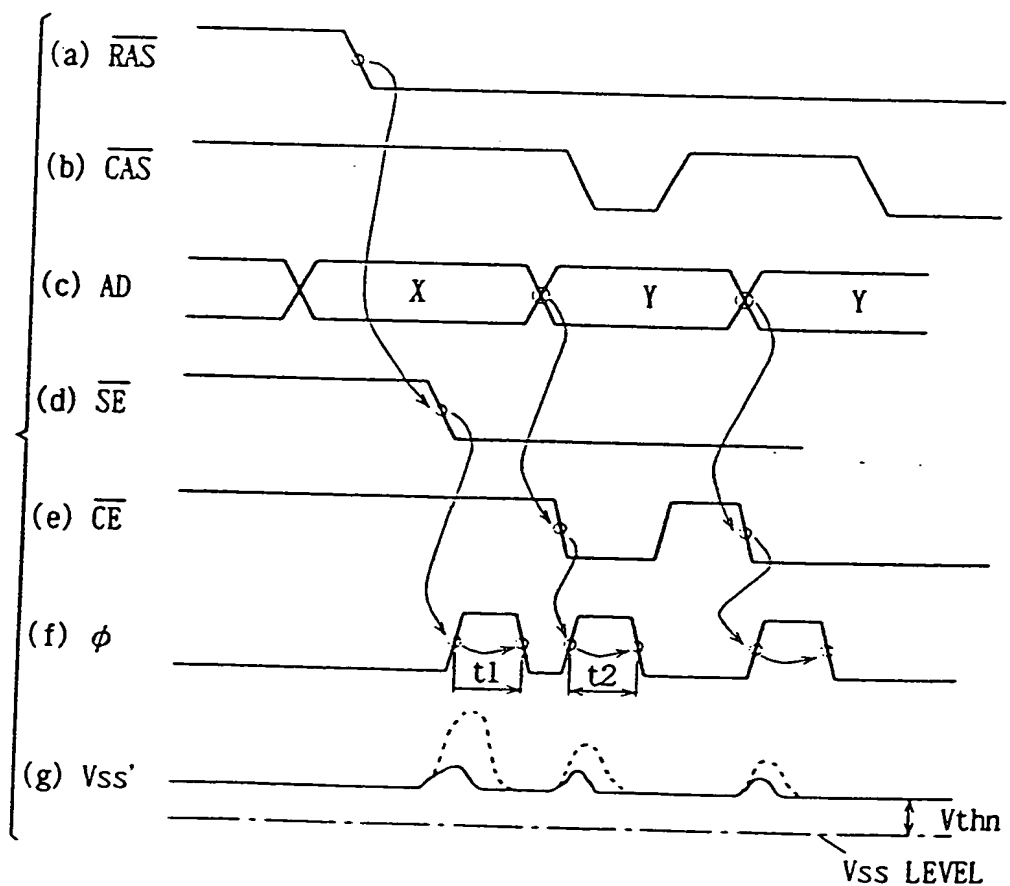


FIG. 9



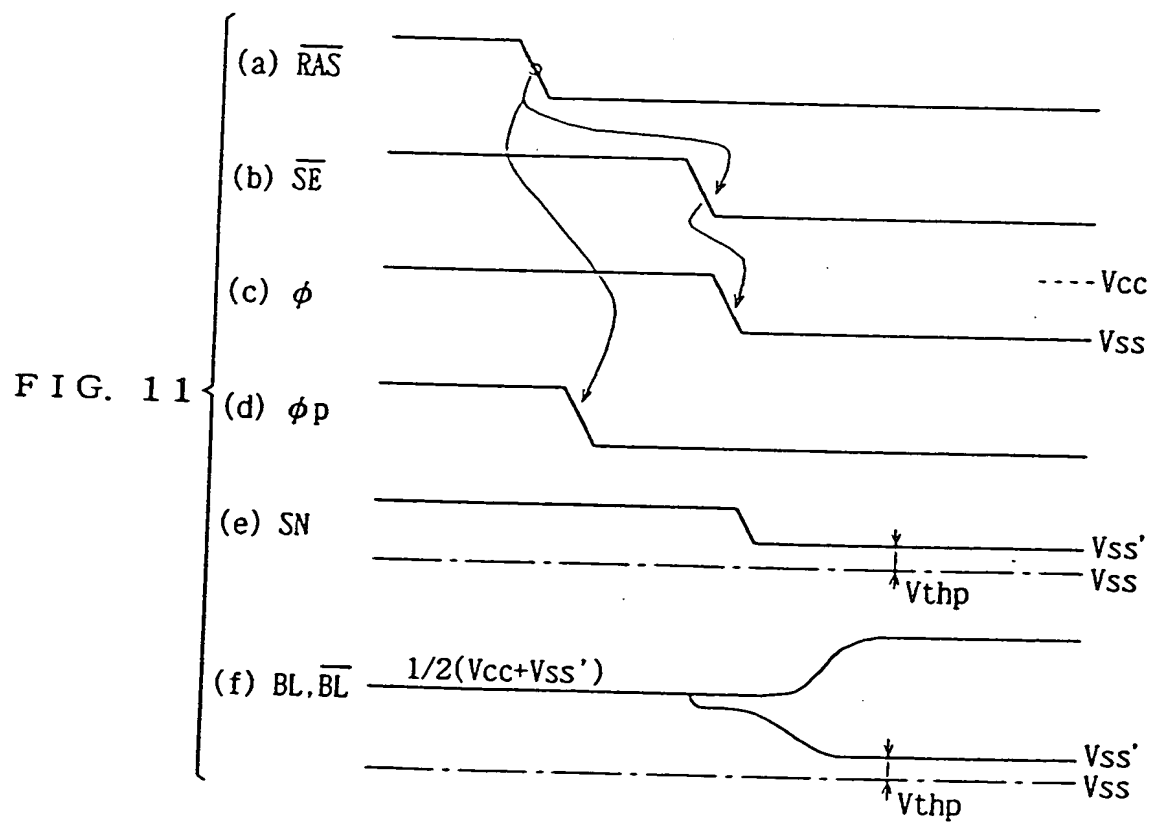


FIG. 12

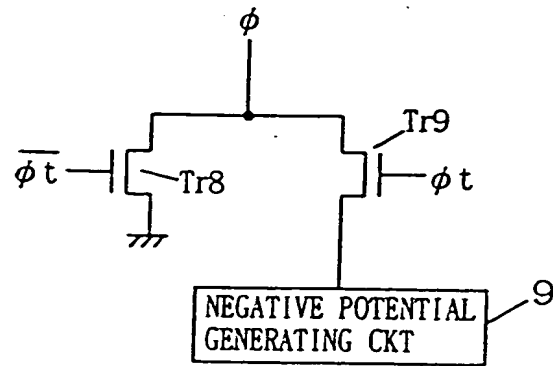
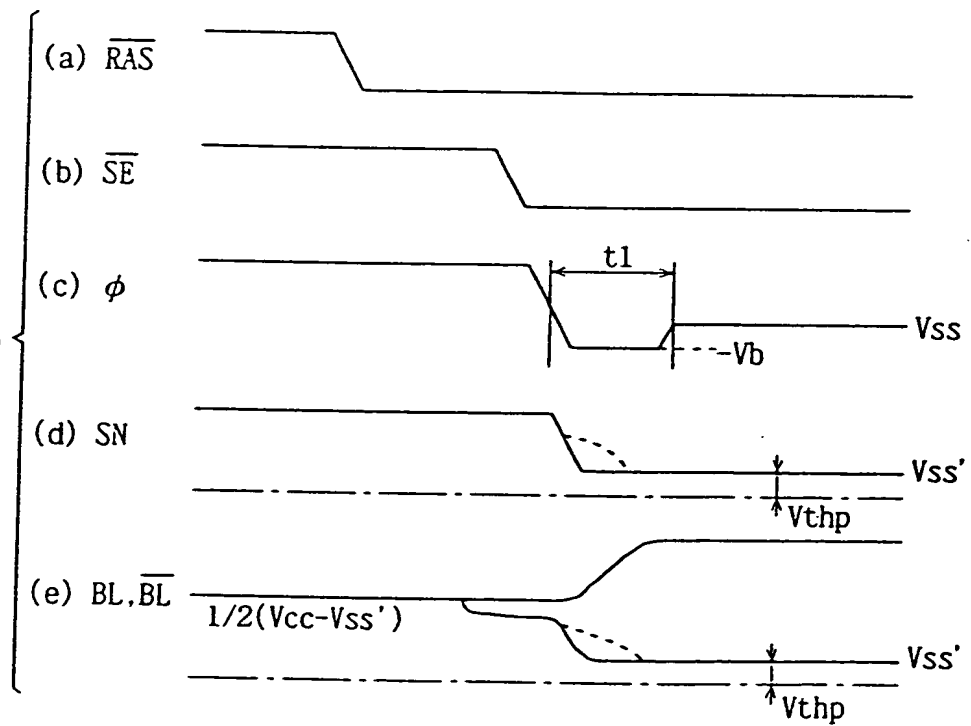


FIG. 13



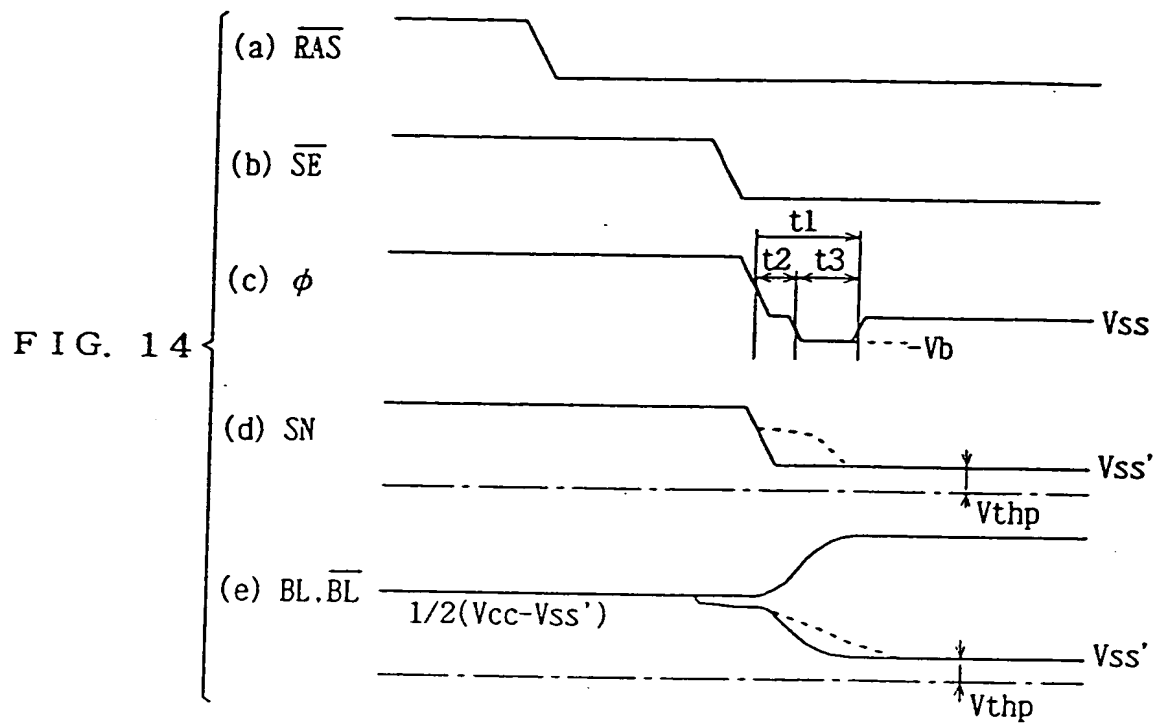


FIG. 15

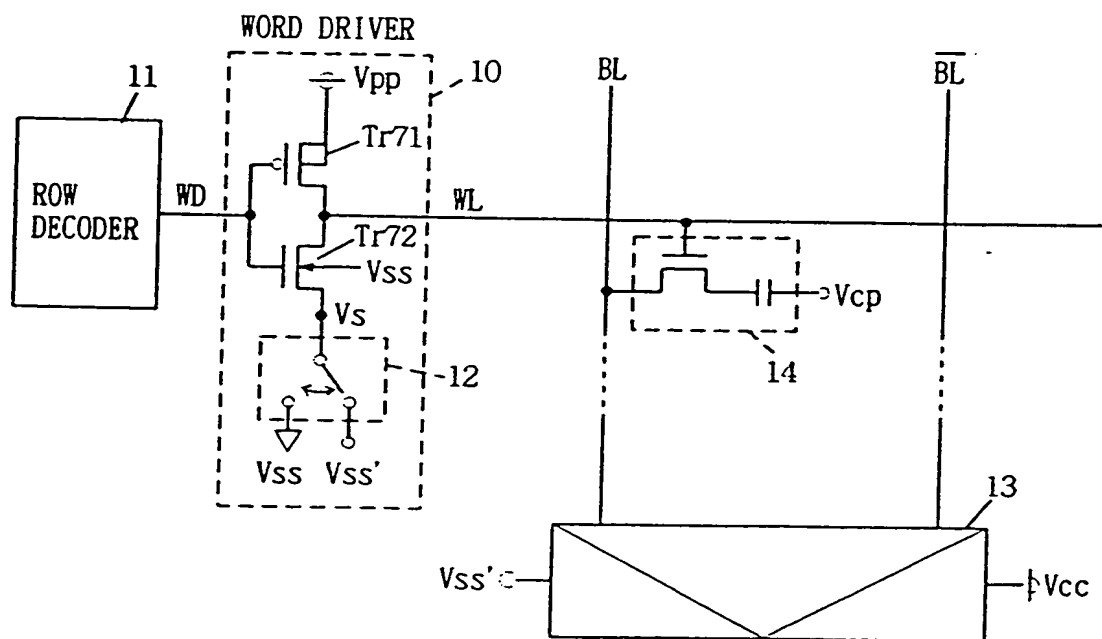


FIG. 16

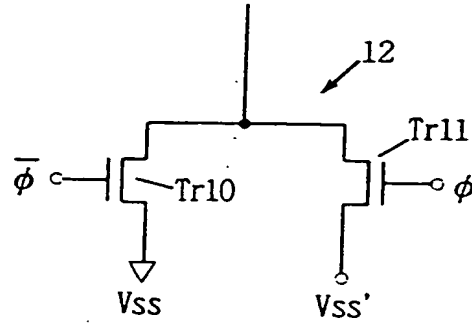


FIG. 17

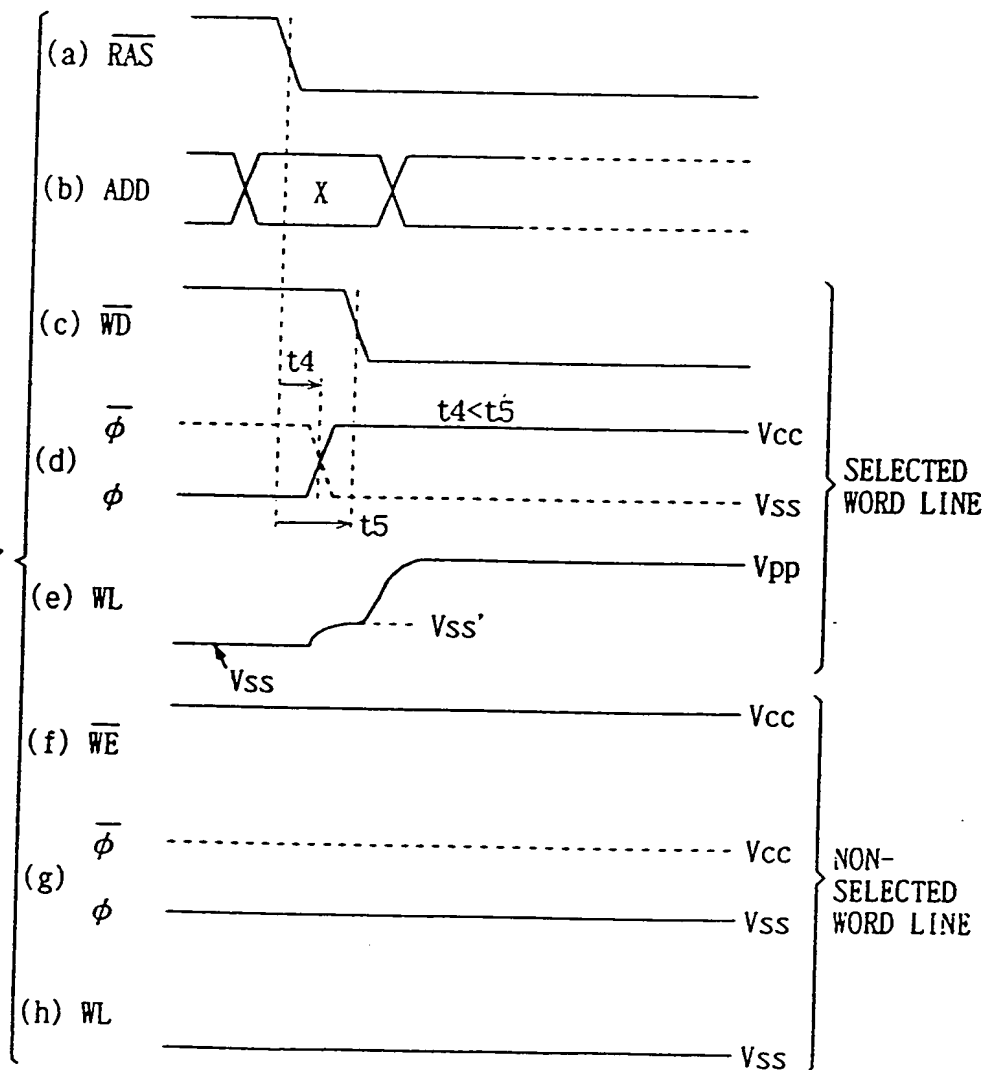


FIG. 18

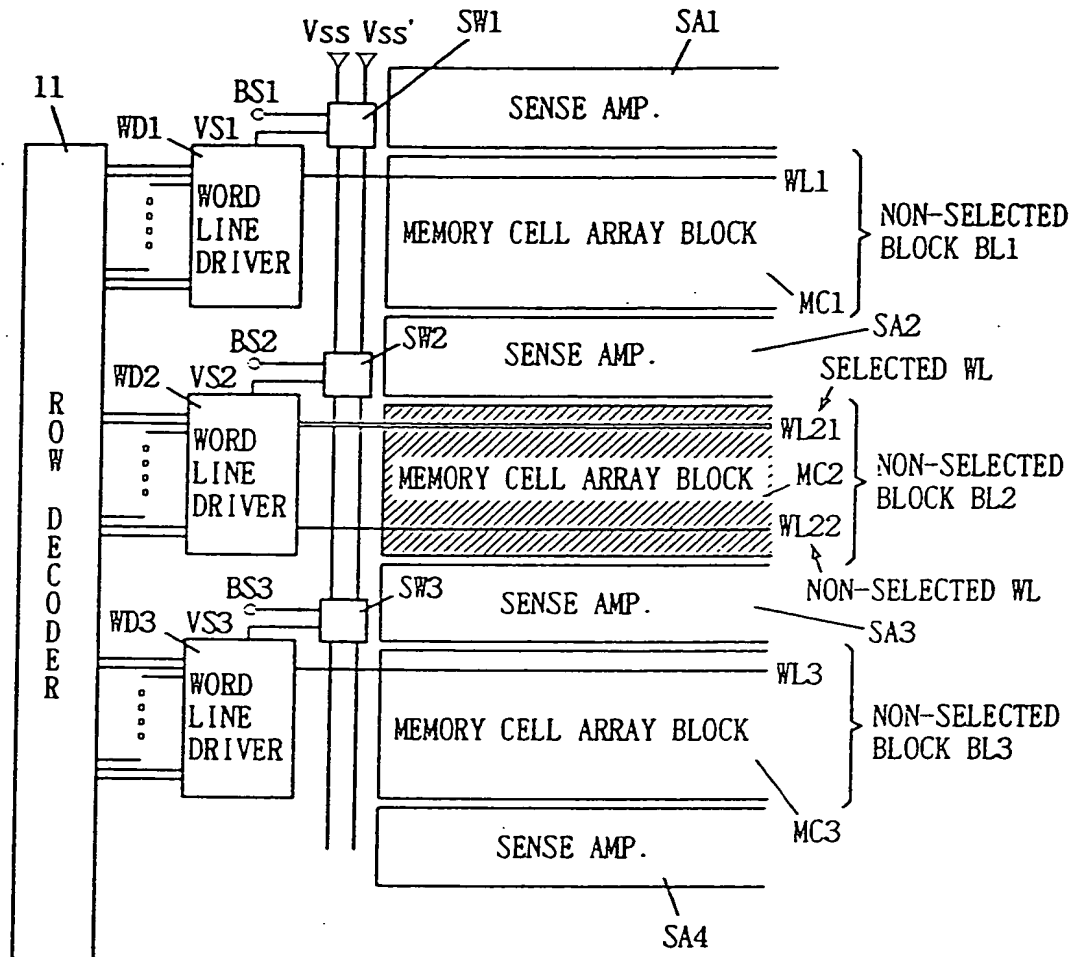
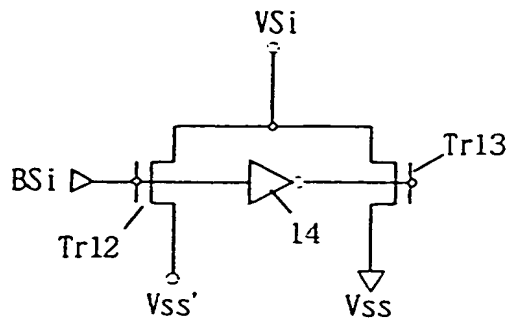


FIG. 19



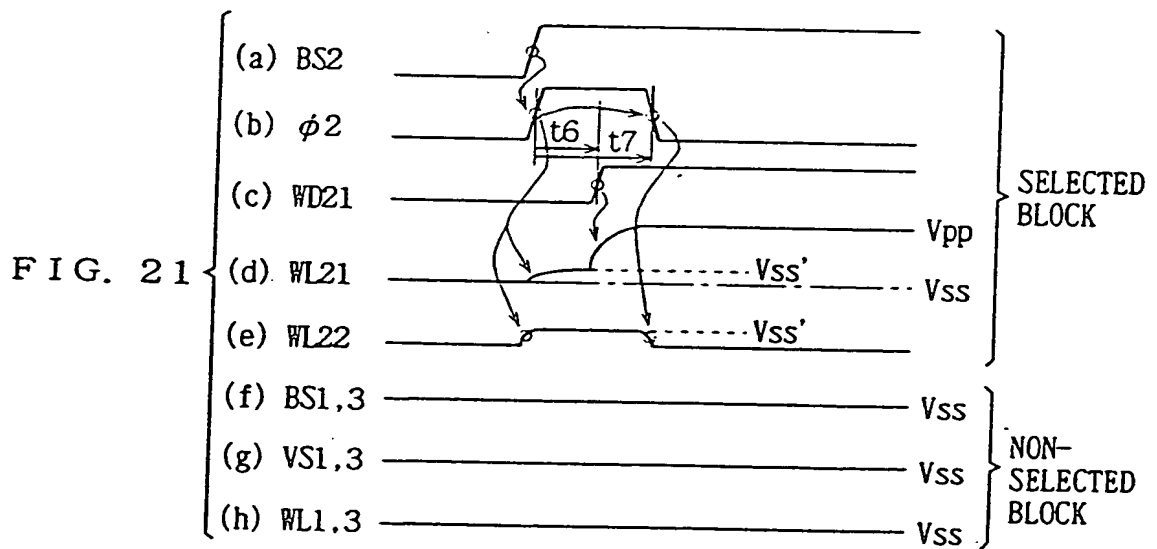
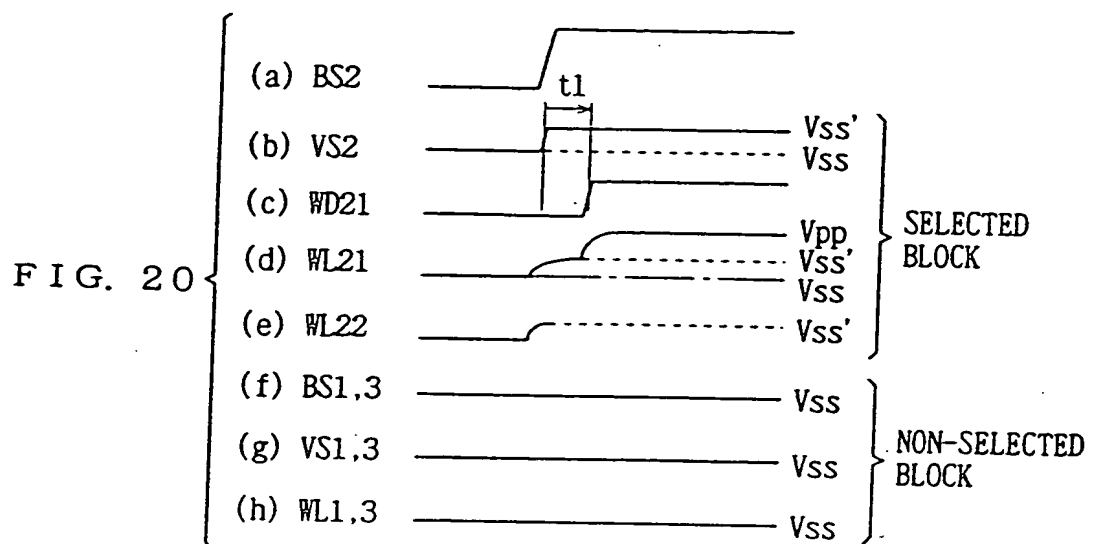


FIG. 22

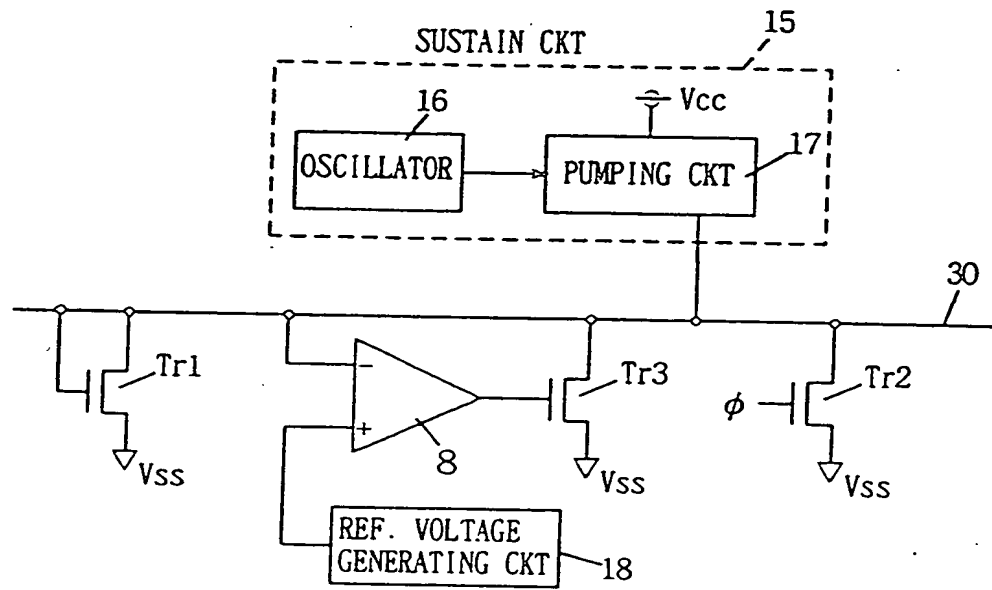
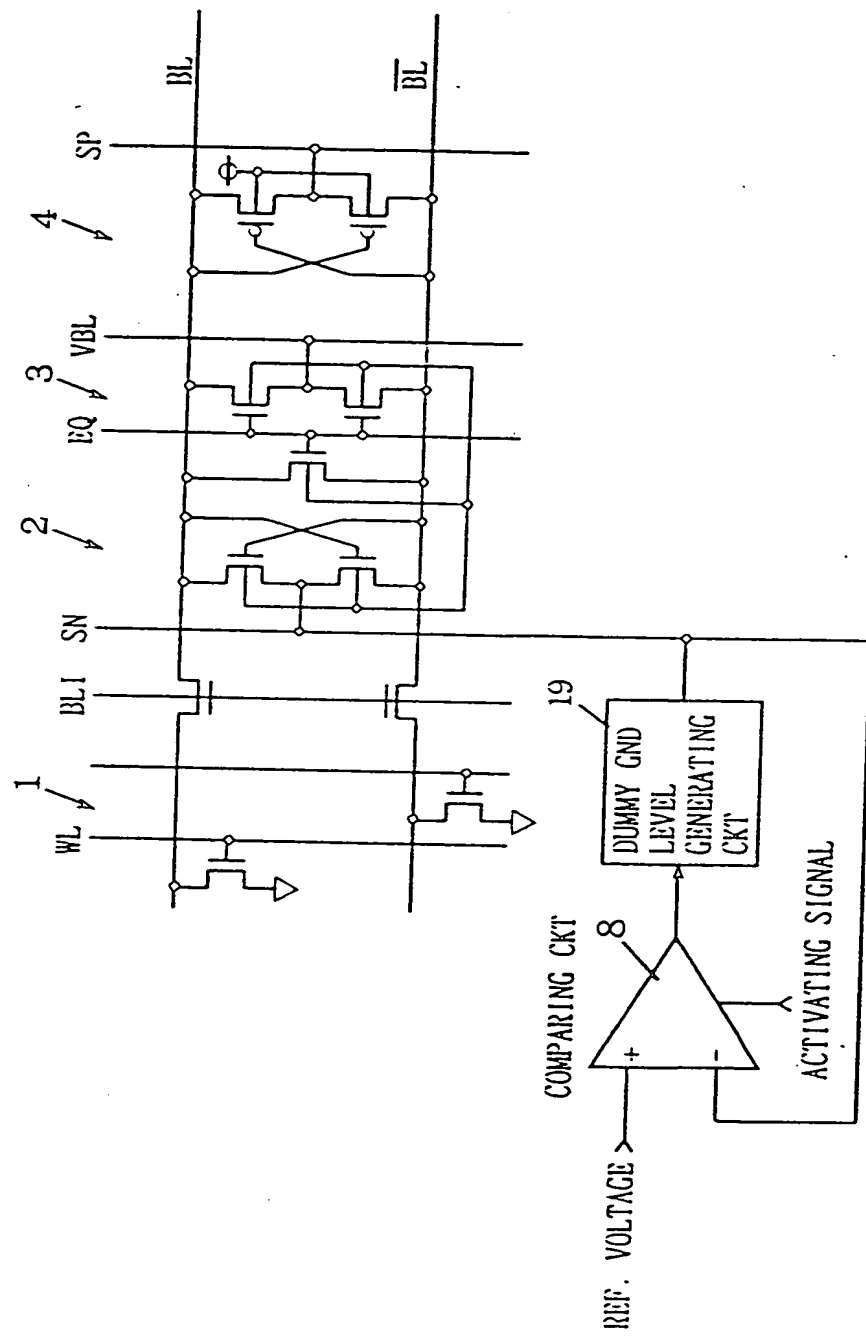


FIG. 23



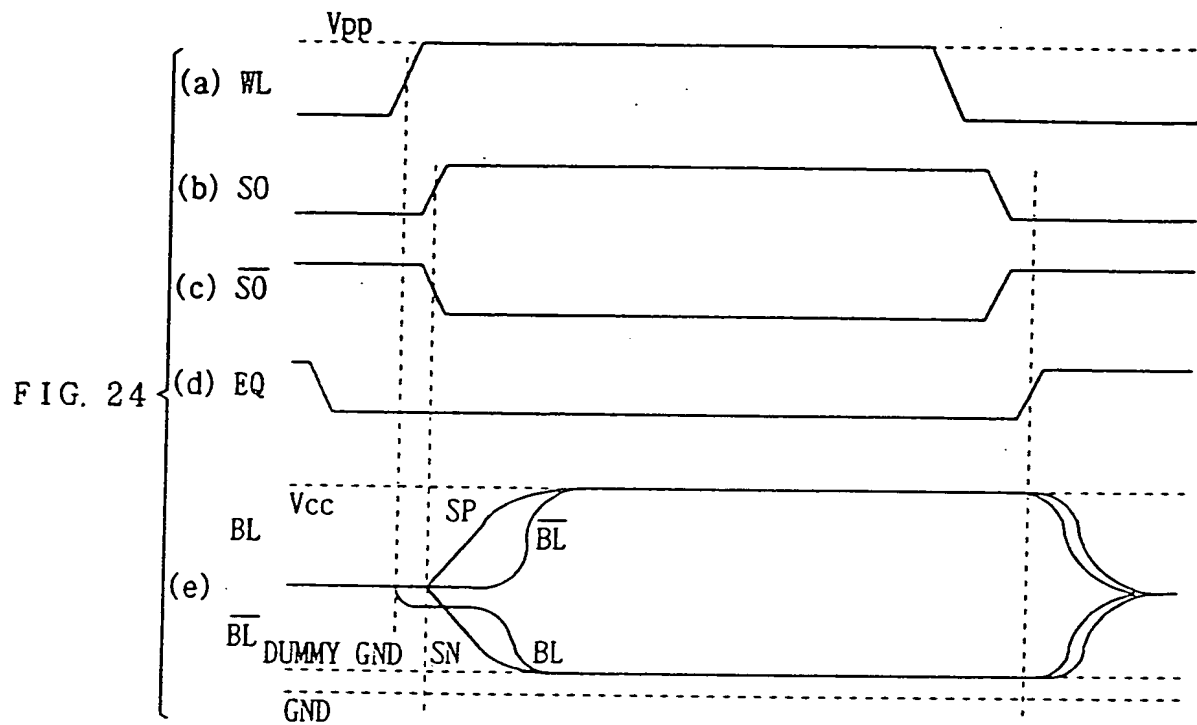


FIG. 25

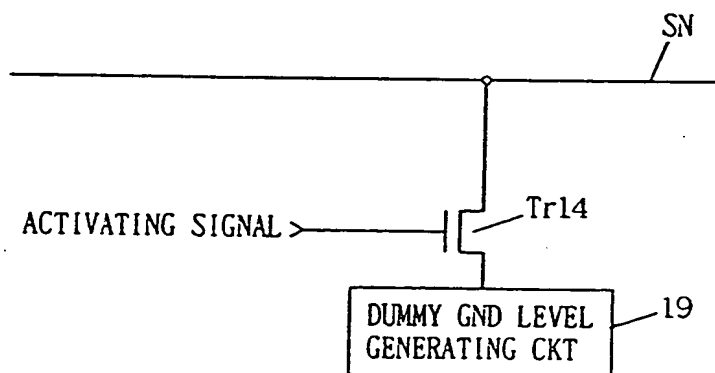


FIG. 26

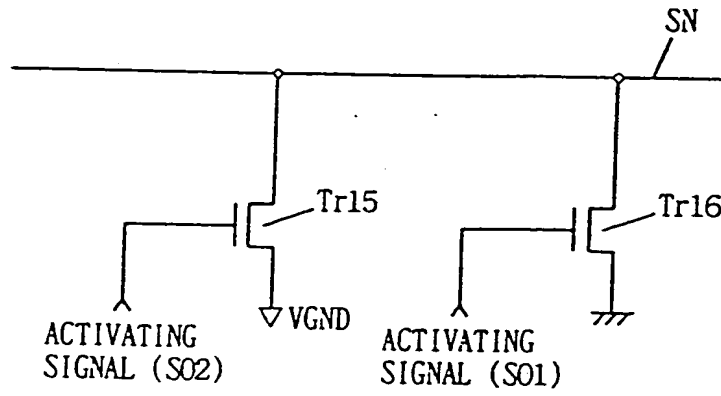


FIG. 27

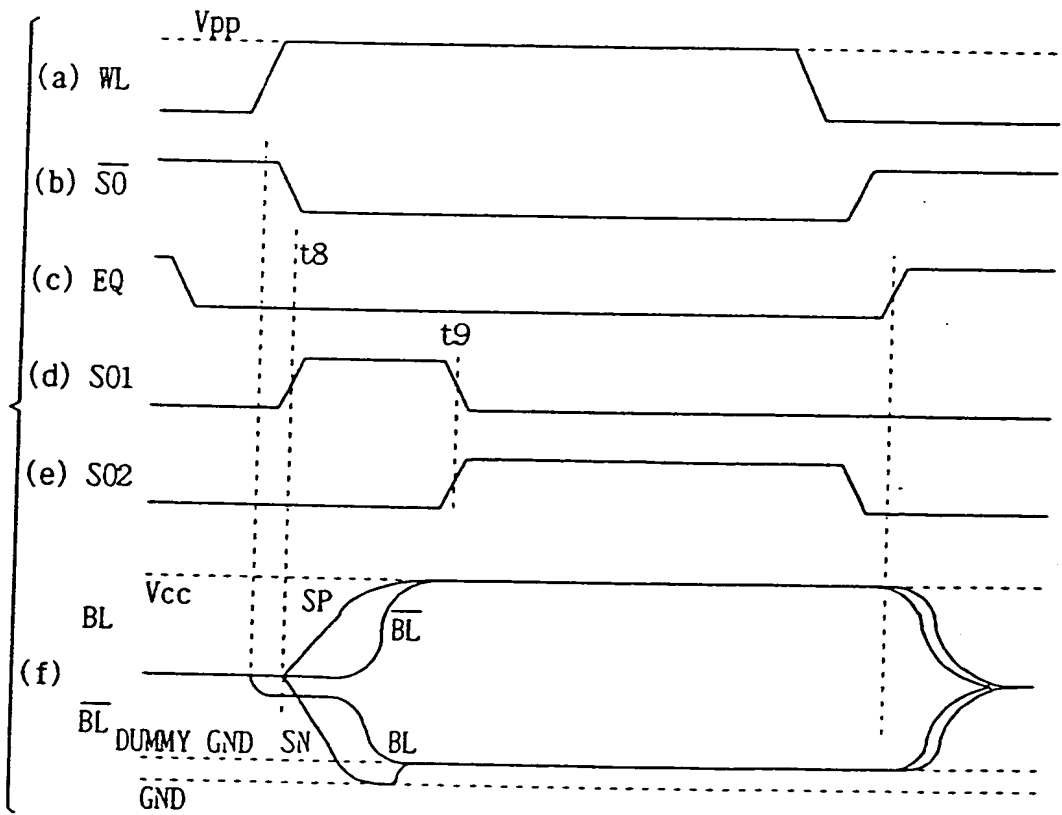


FIG. 28

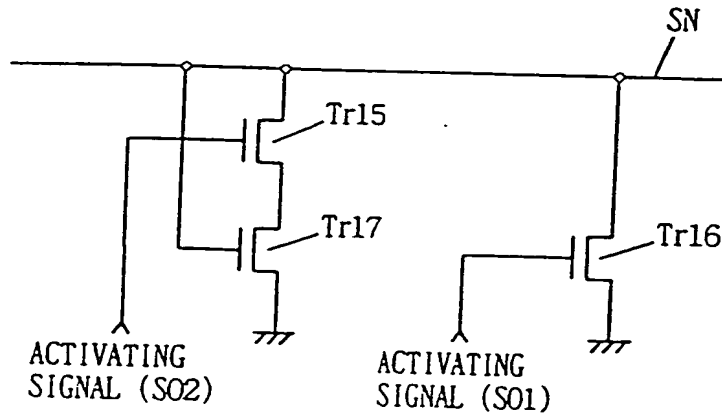


FIG. 29

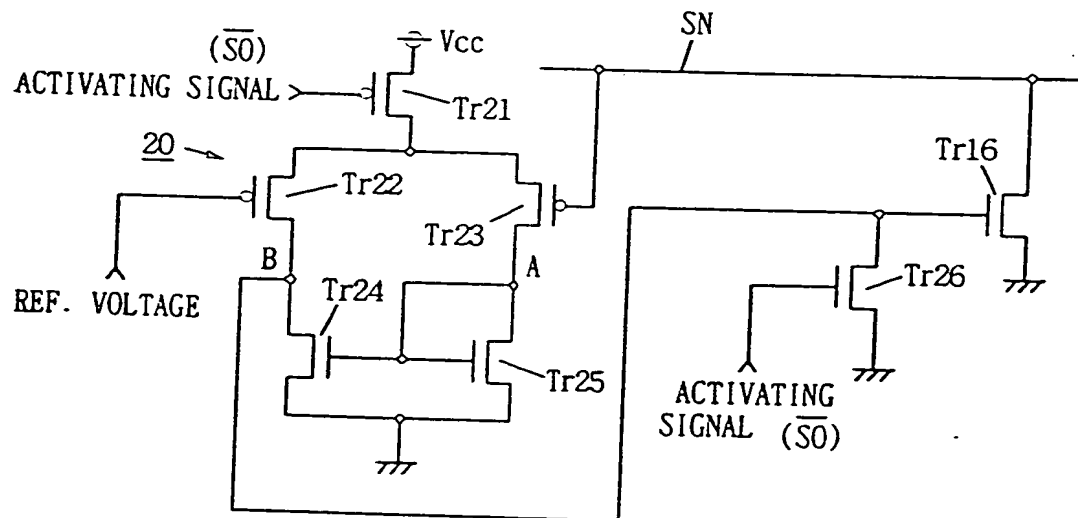


FIG. 32

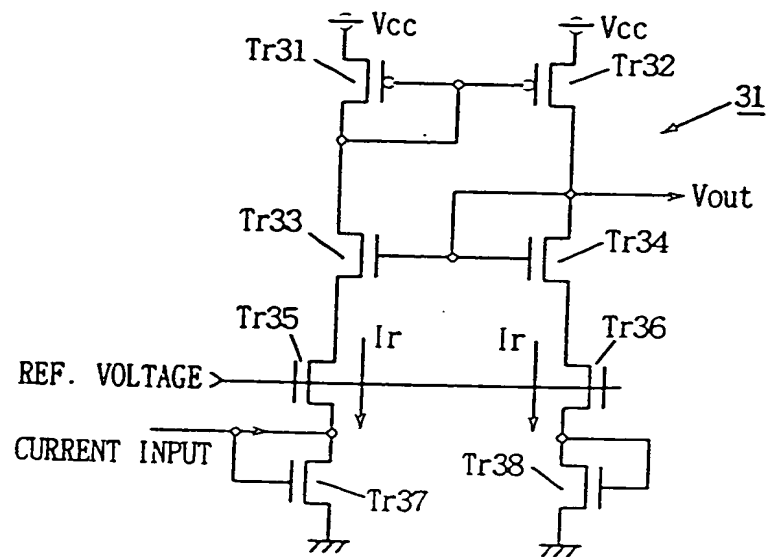


FIG. 33

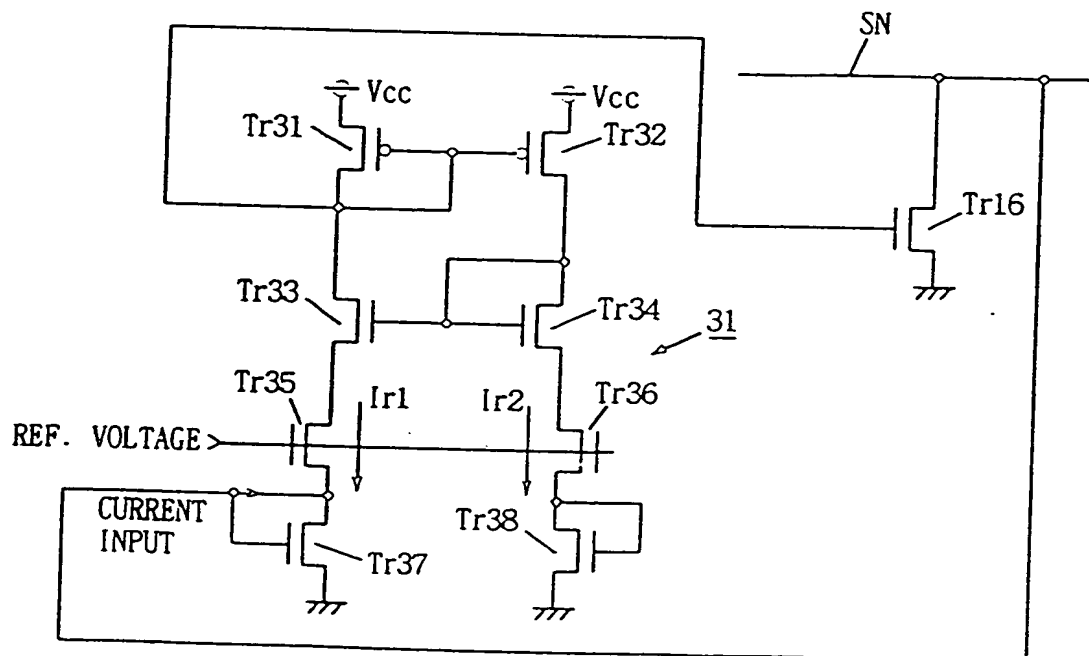


FIG. 34

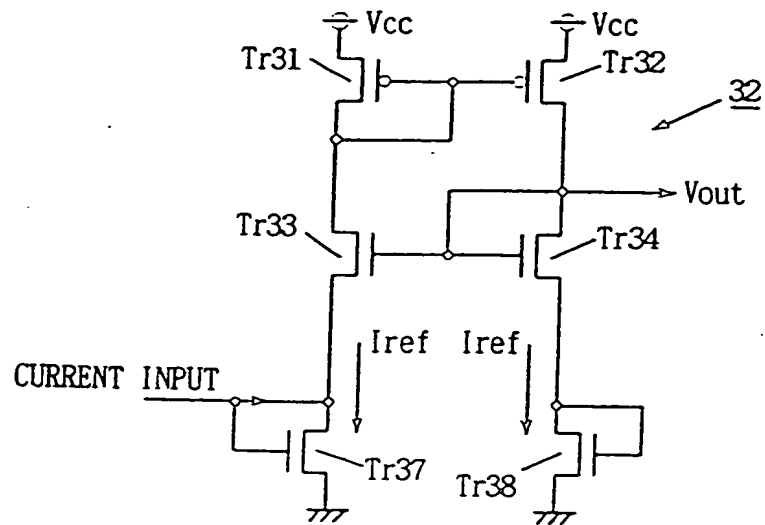


FIG. 35

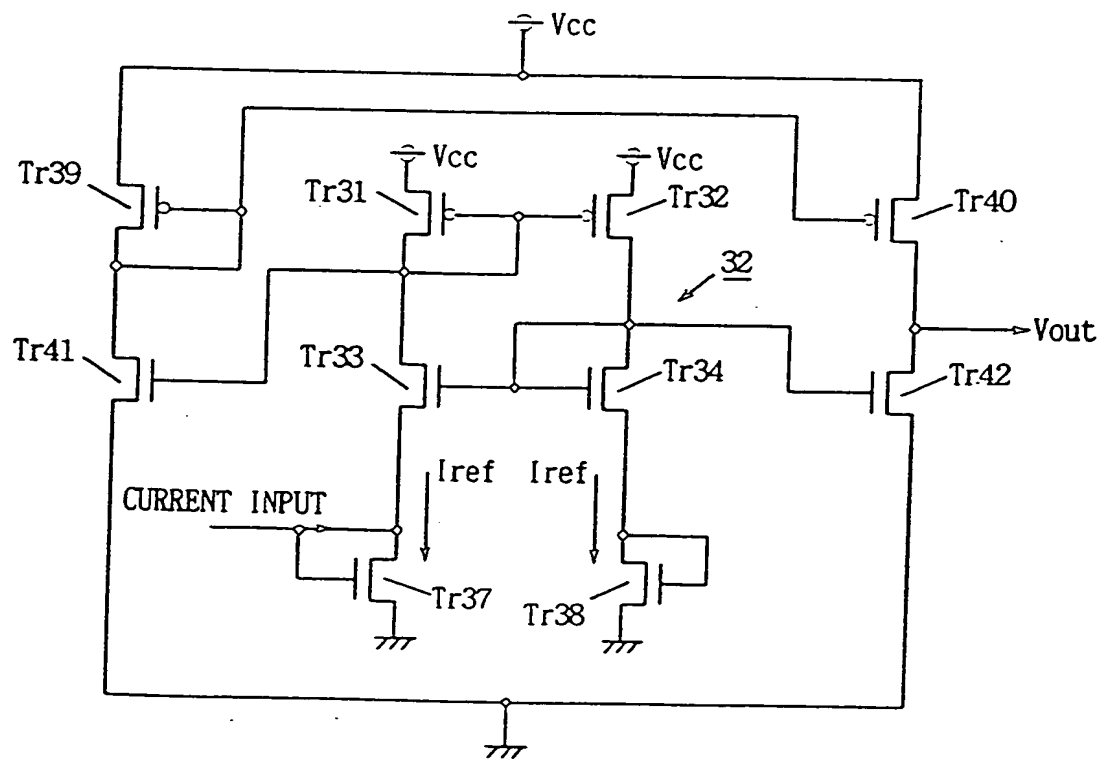


FIG. 36

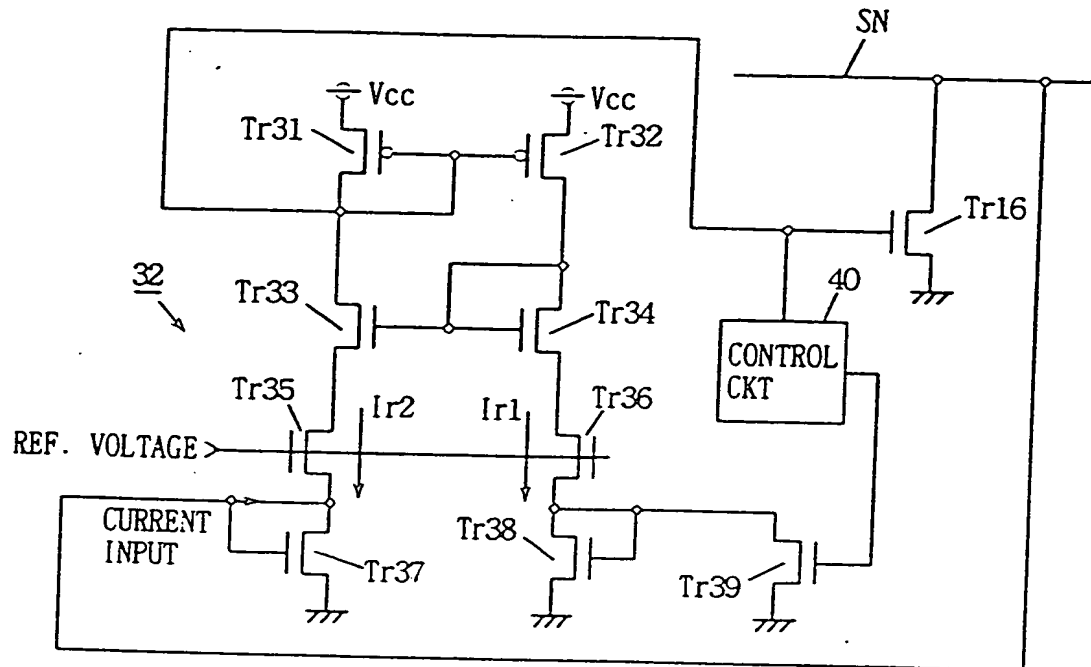


FIG. 37

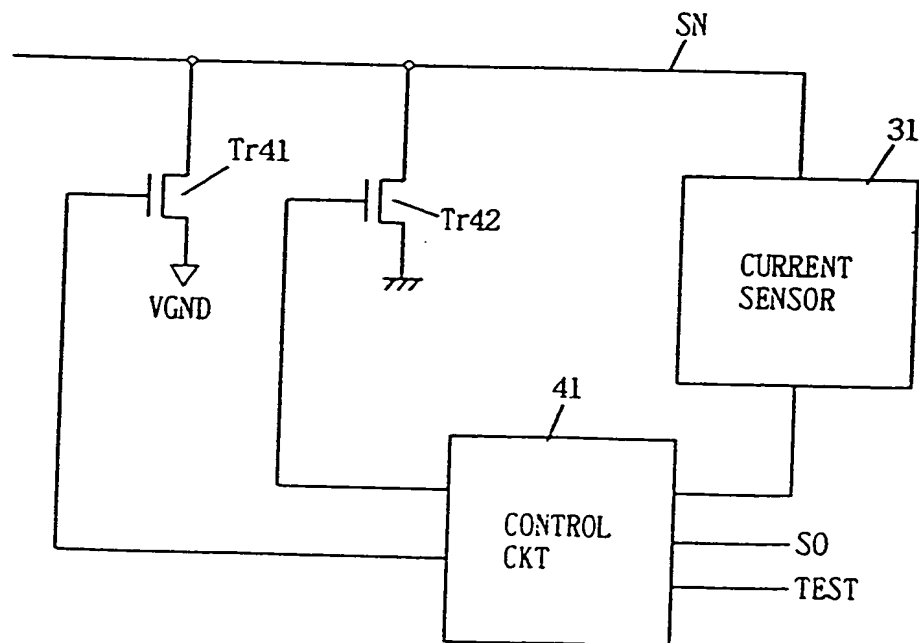


FIG. 38

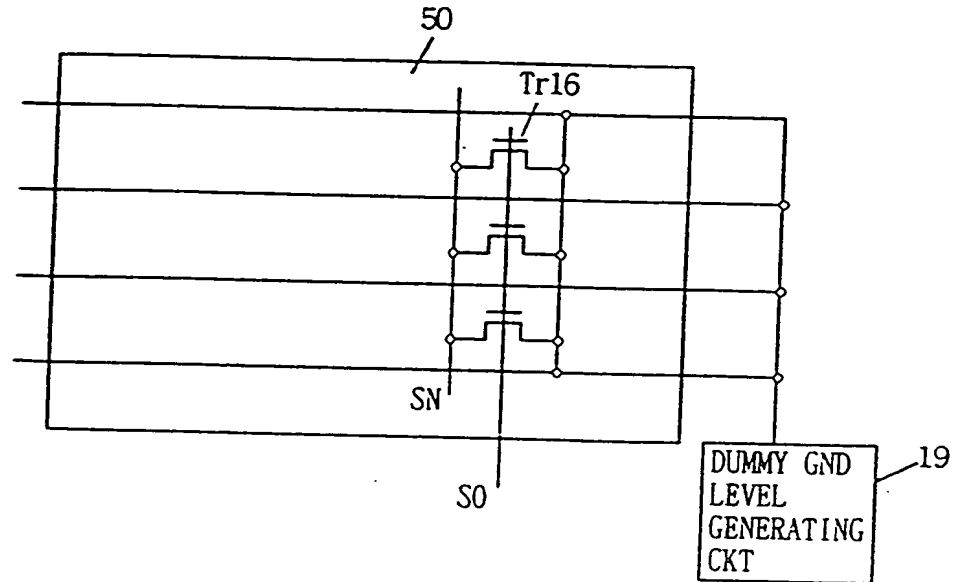


FIG. 39

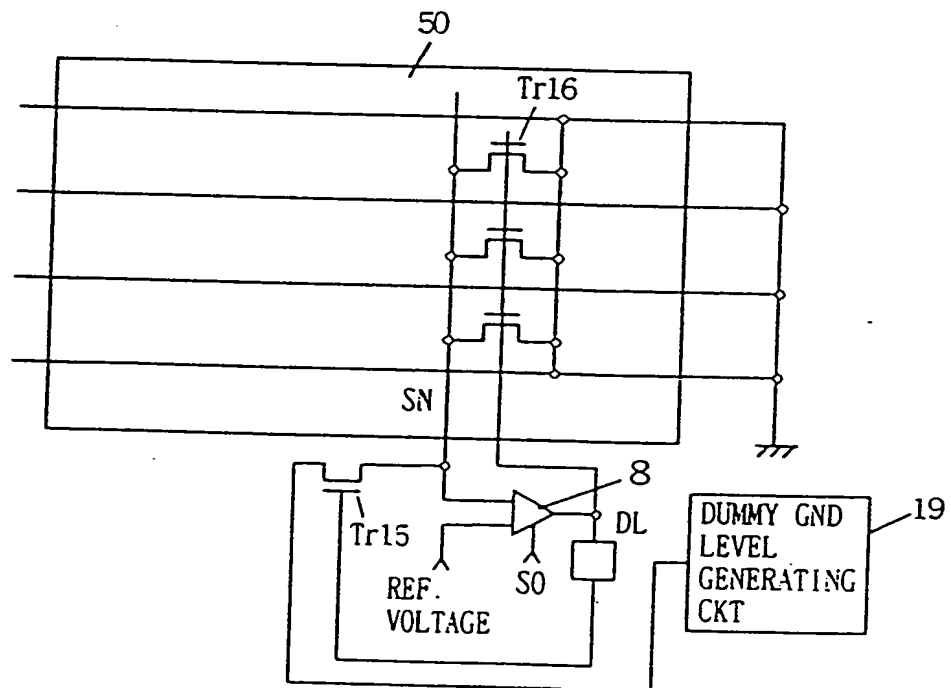


FIG. 40

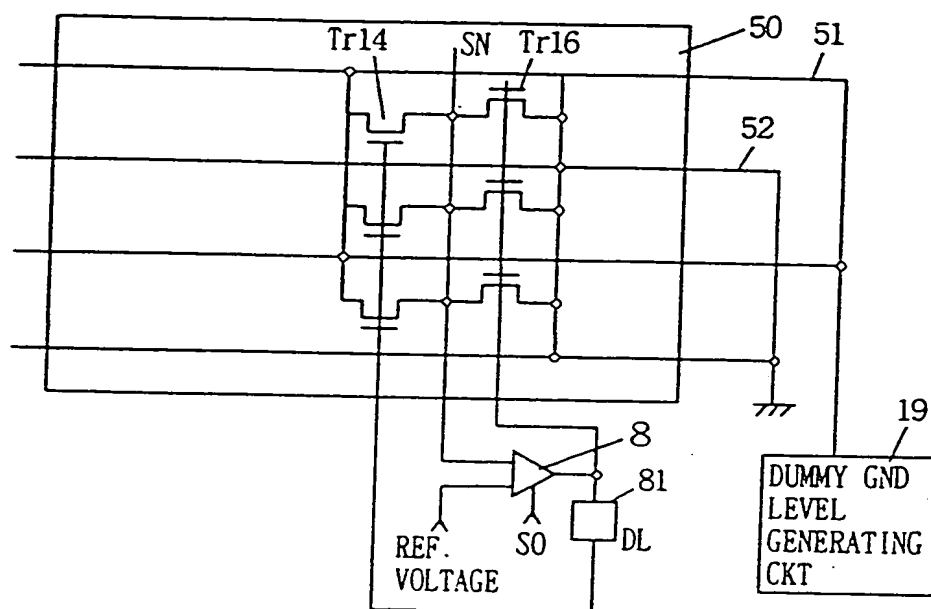


FIG. 41

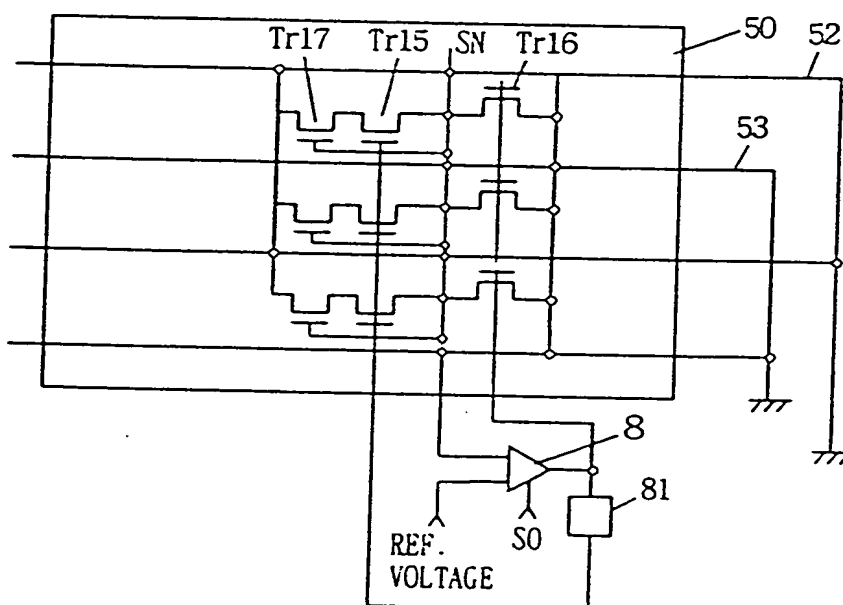


FIG. 42

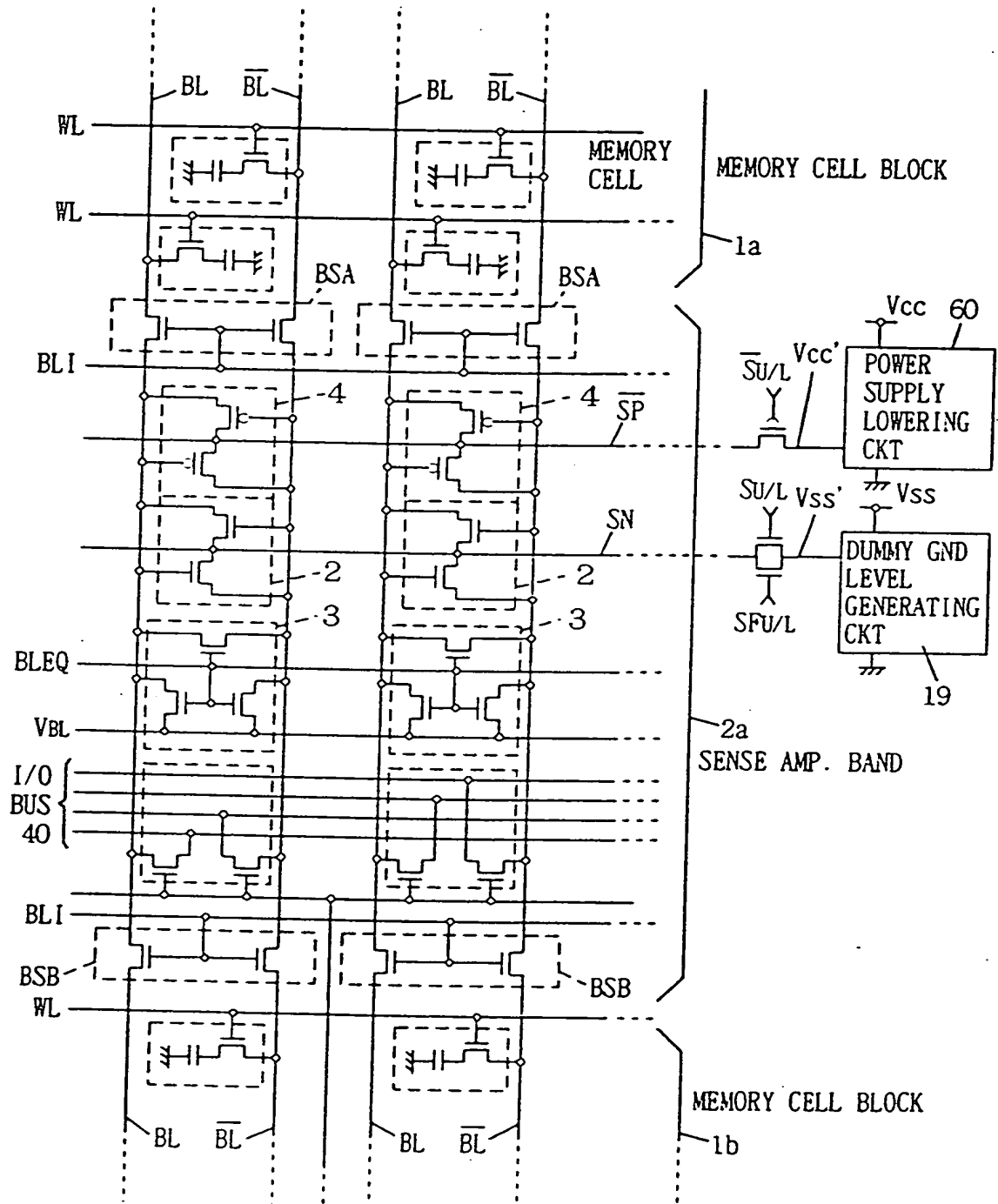


FIG. 43

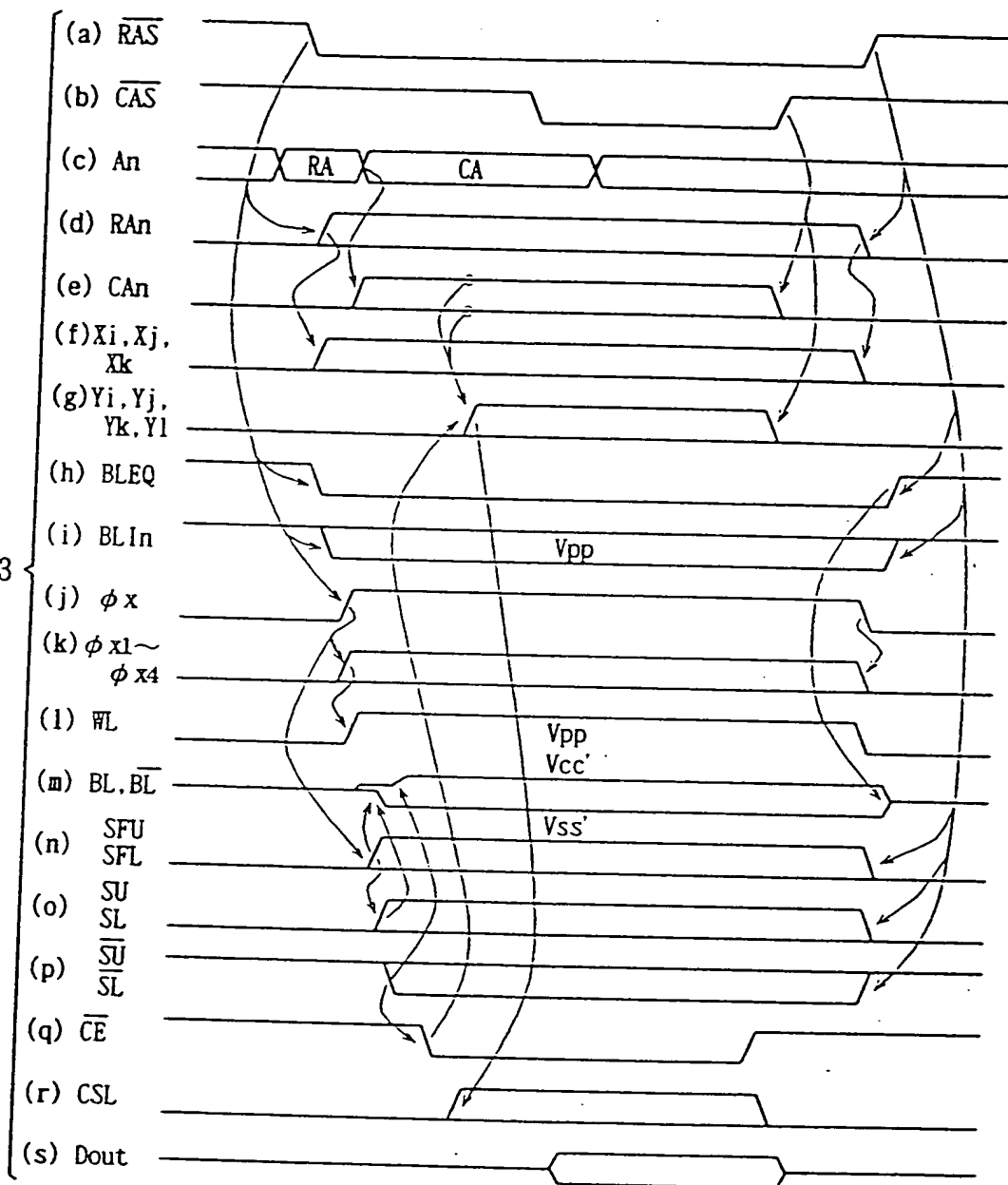


FIG. 44

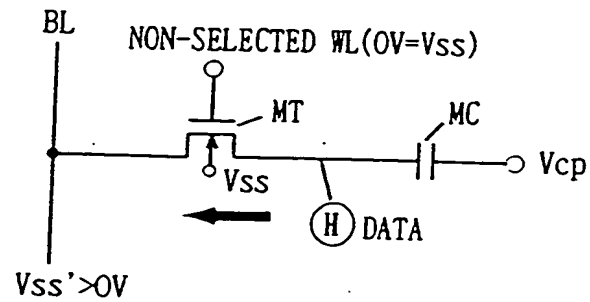


FIG. 45

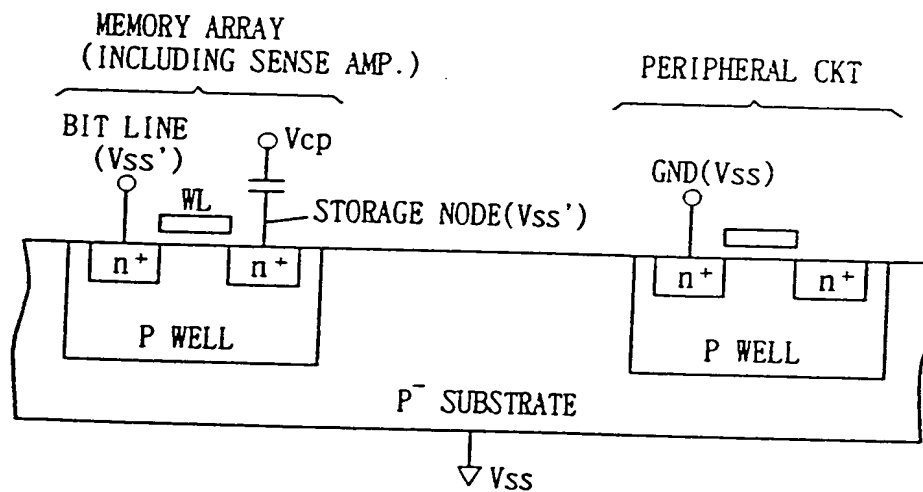


FIG. 46

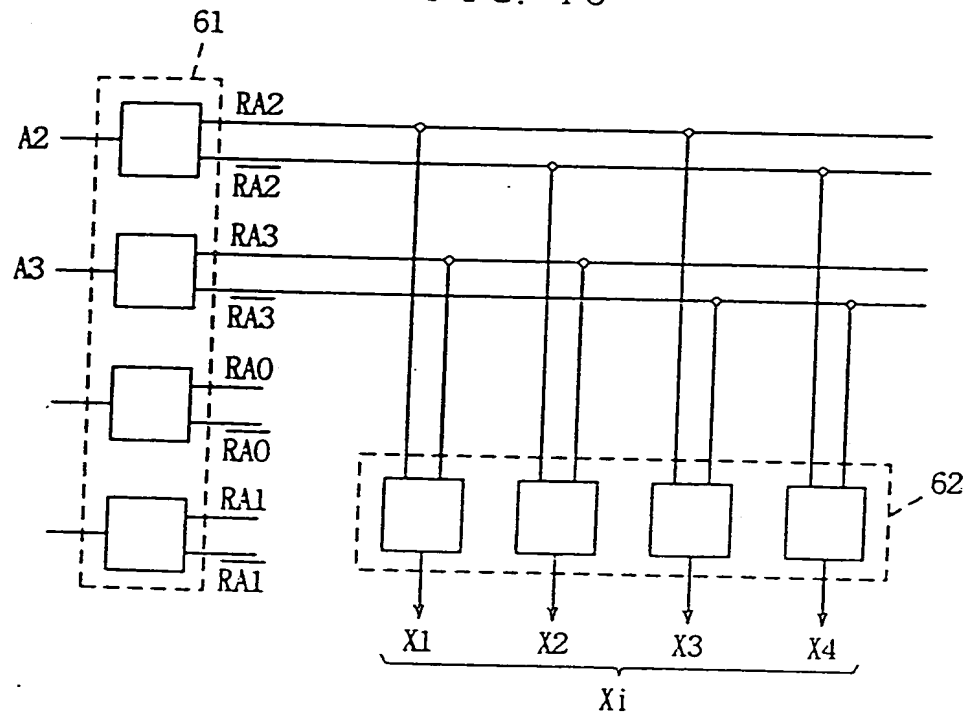


FIG. 47

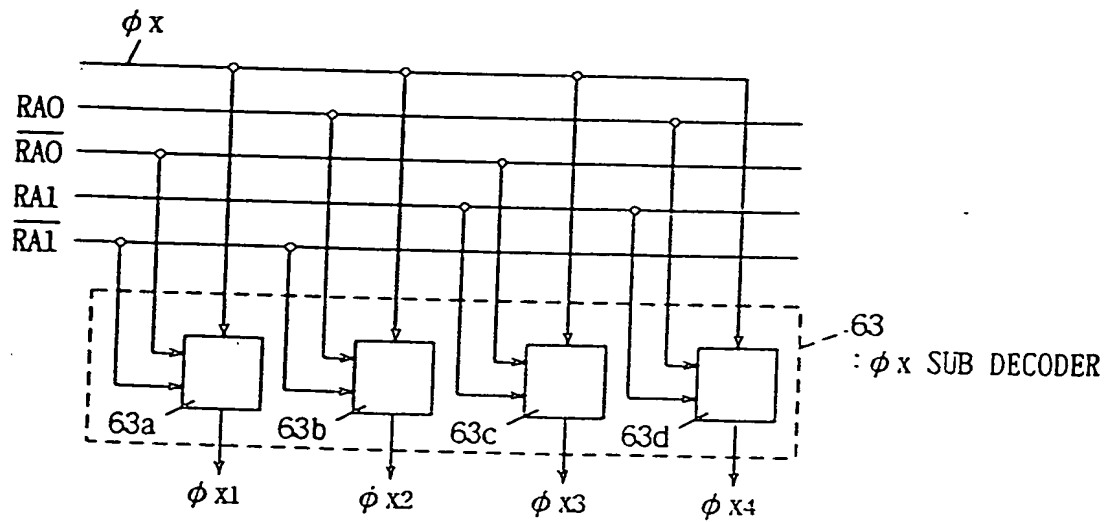


FIG. 48

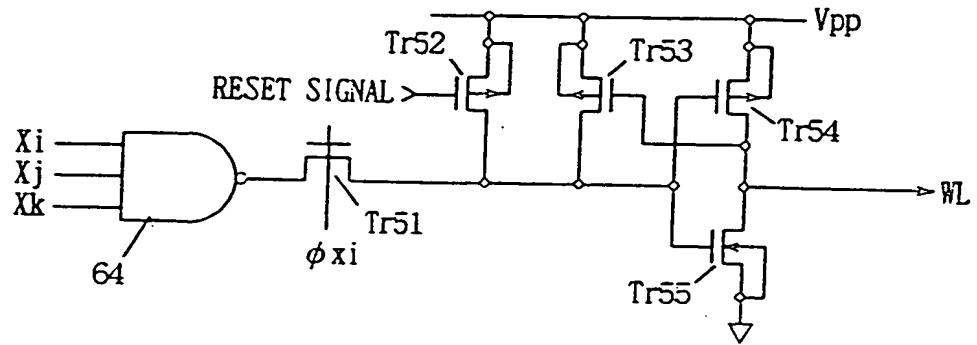


FIG. 49

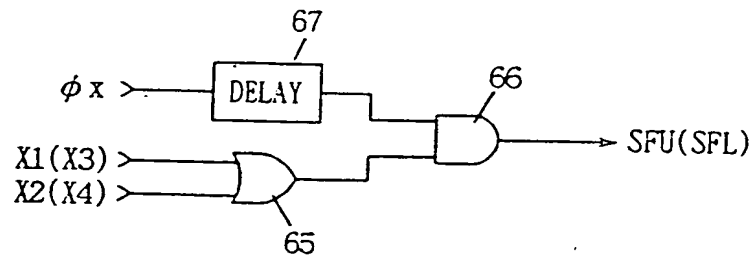
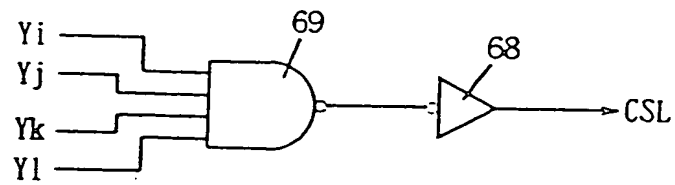


FIG. 50



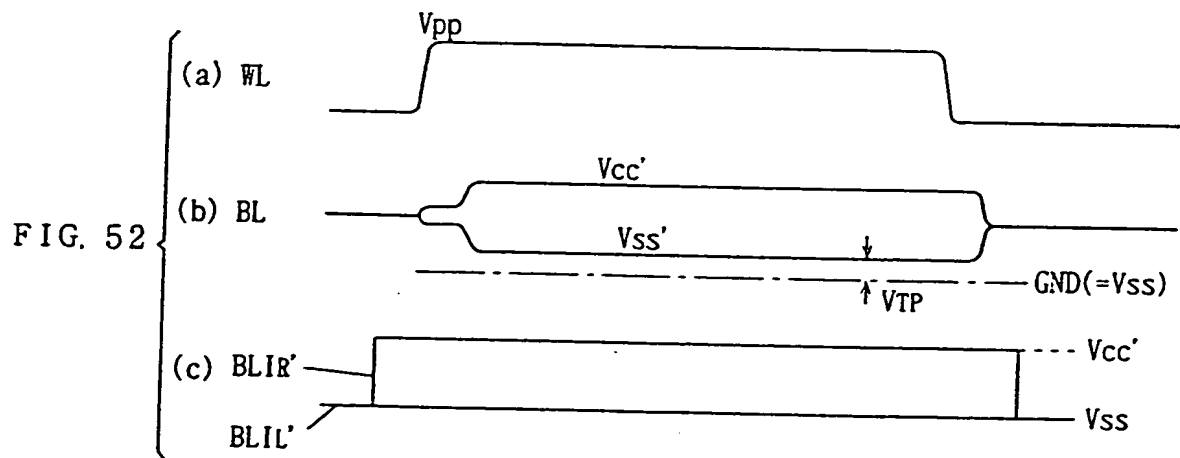
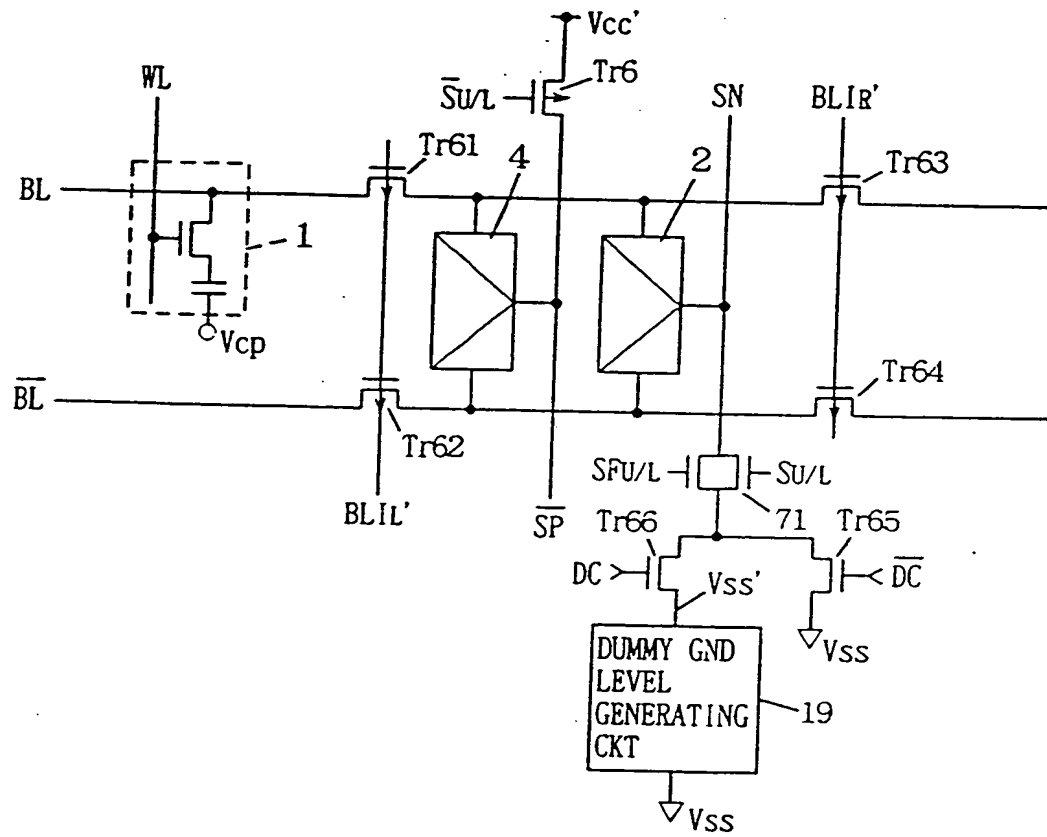


FIG. 53



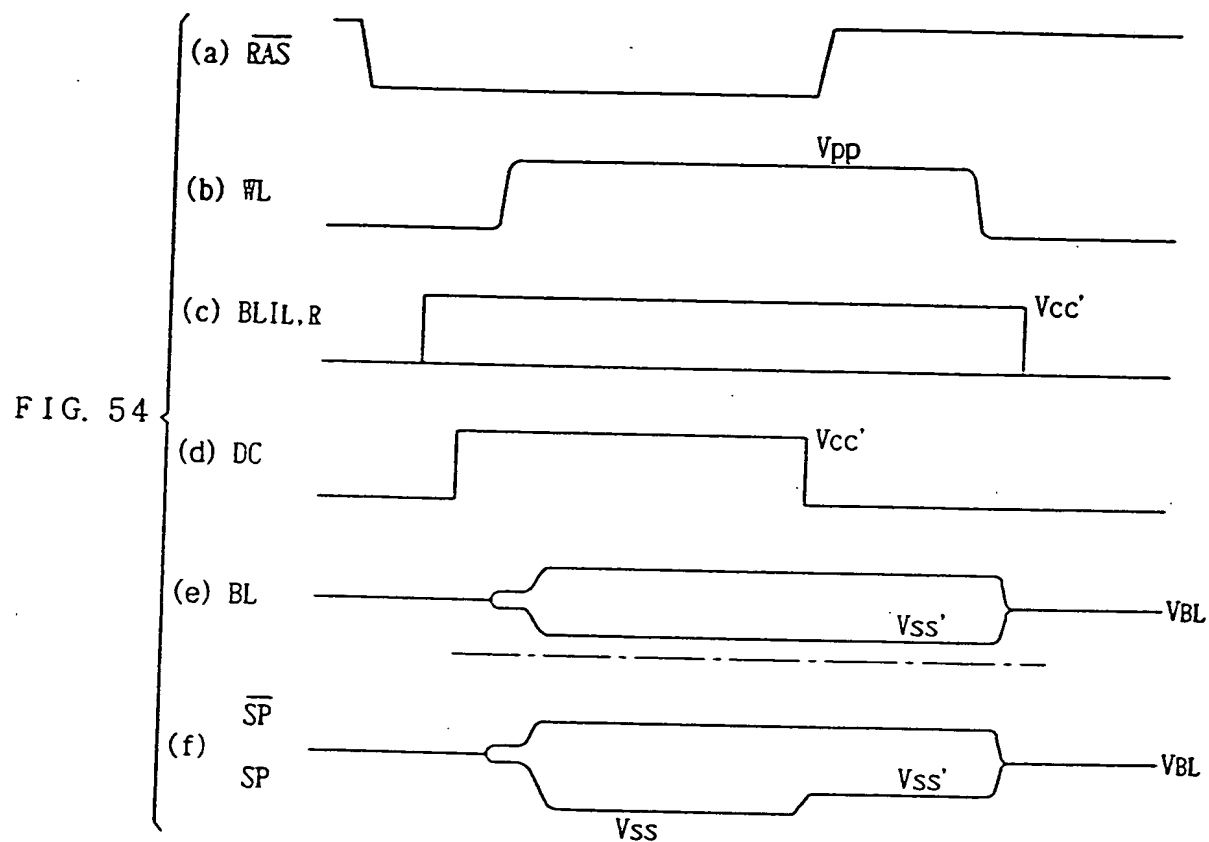
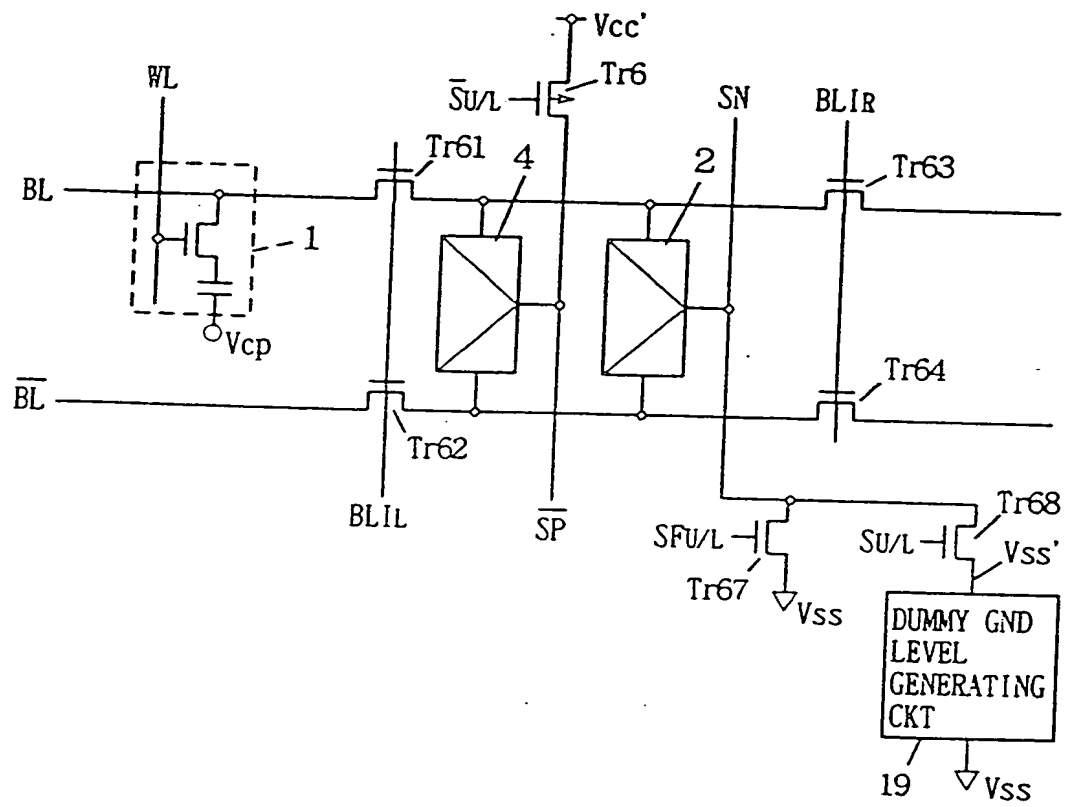


FIG. 55



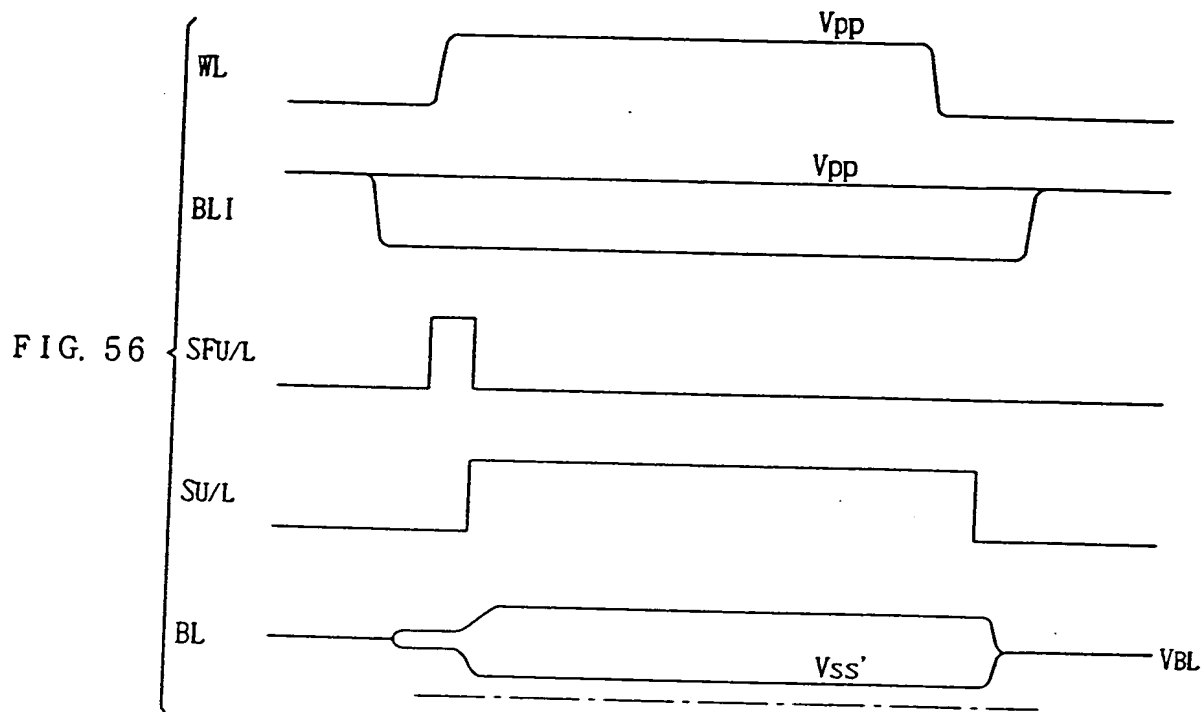


FIG. 57

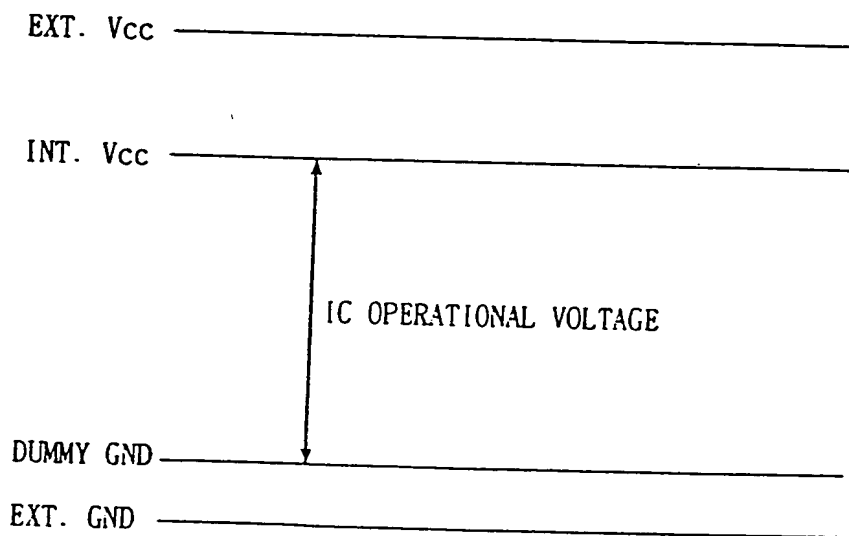


FIG. 58

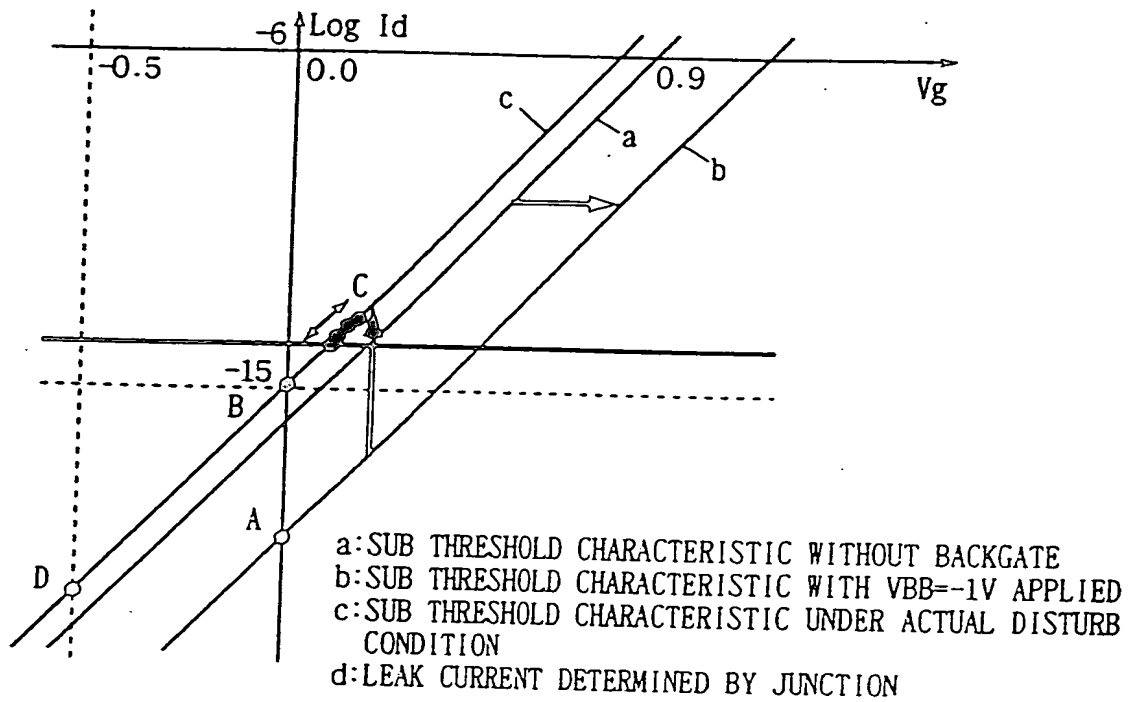


FIG. 59

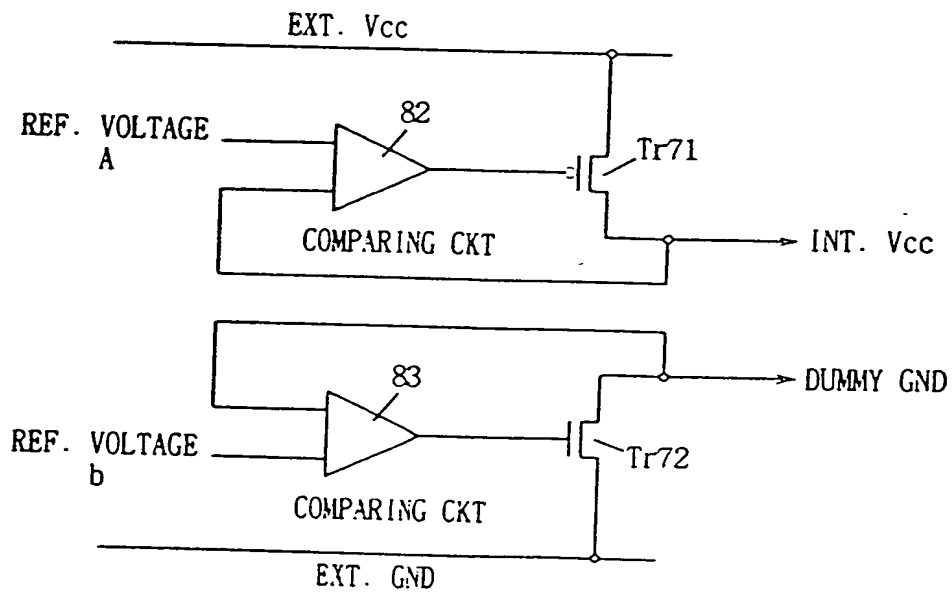


FIG. 60

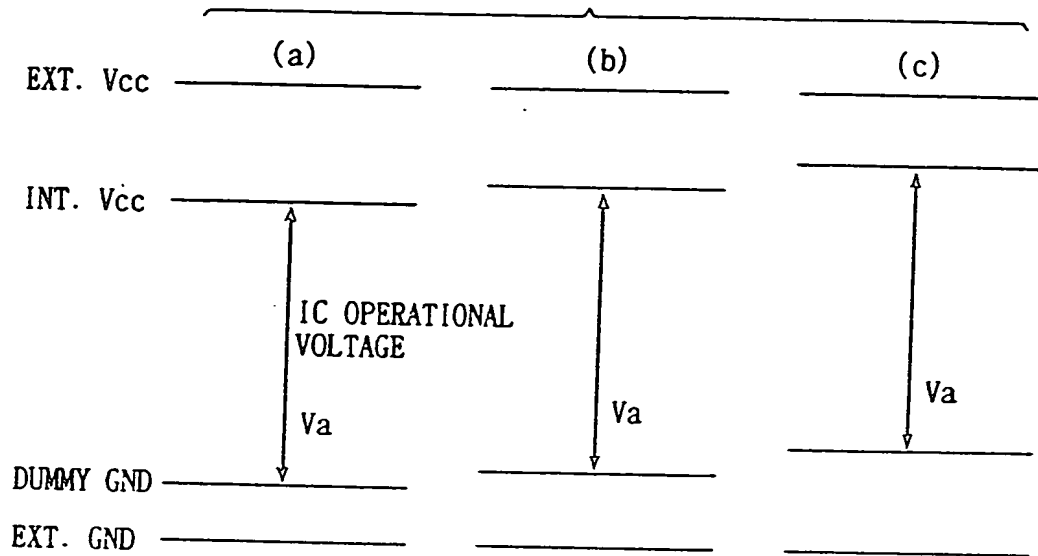


FIG. 61

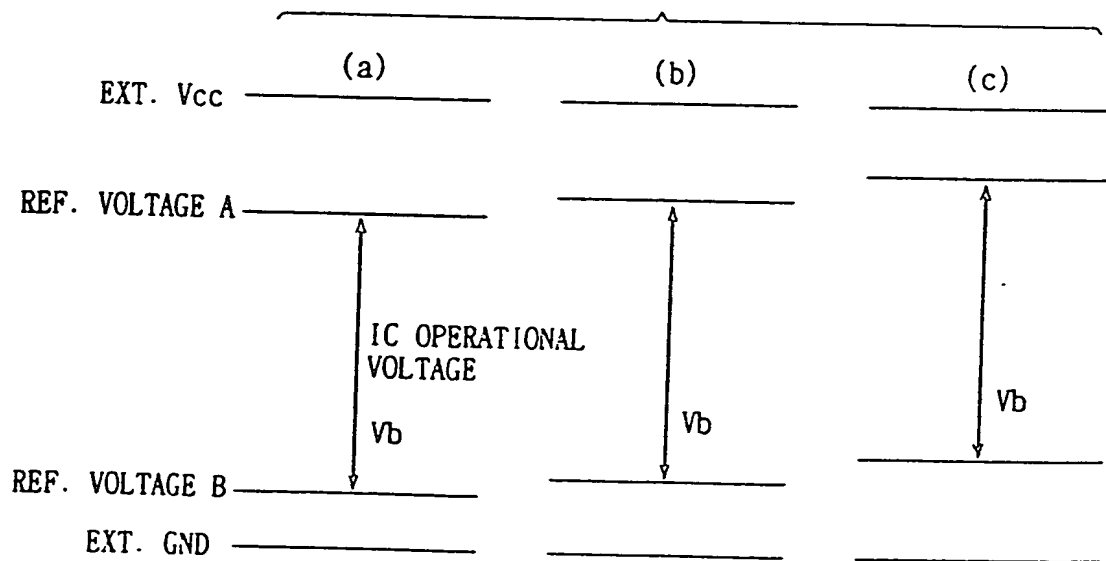


FIG. 62

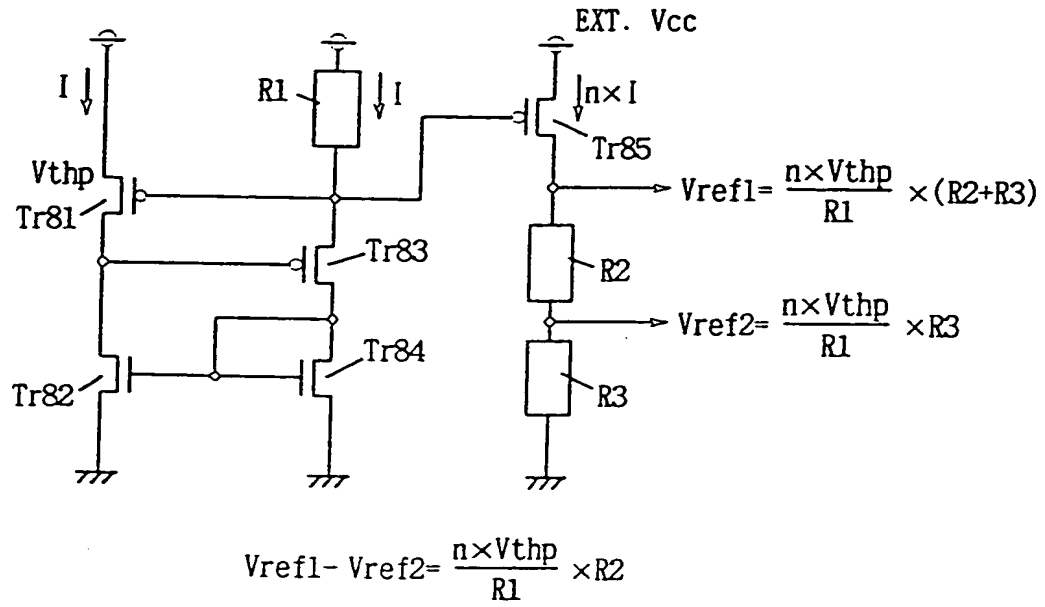


FIG. 63

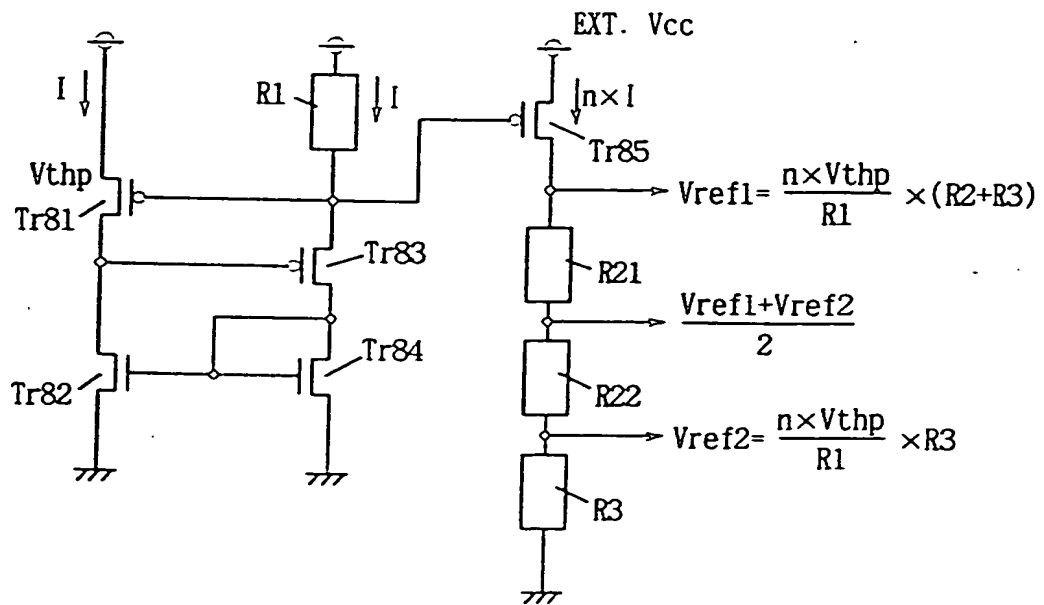
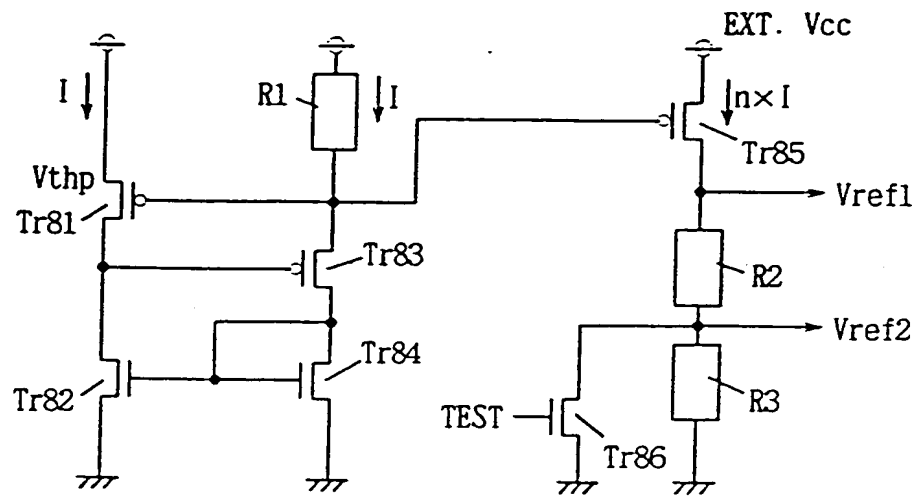


FIG. 64



The diagram shows a timing relationship between a TEST signal and two reference voltage signals, Vref1 and Vref2. The TEST signal is a trapezoidal pulse that rises, stays high for a duration indicated by a dotted line, and then falls. Vref1 and Vref2 are signals that transition from a high state to a low state during the rising edge of the TEST signal and from a low state back to a high state during the falling edge of the TEST signal. Vertical double-headed arrows indicate the time intervals between the TEST signal's edges and the corresponding transitions of Vref1 and Vref2.

FIG. 67

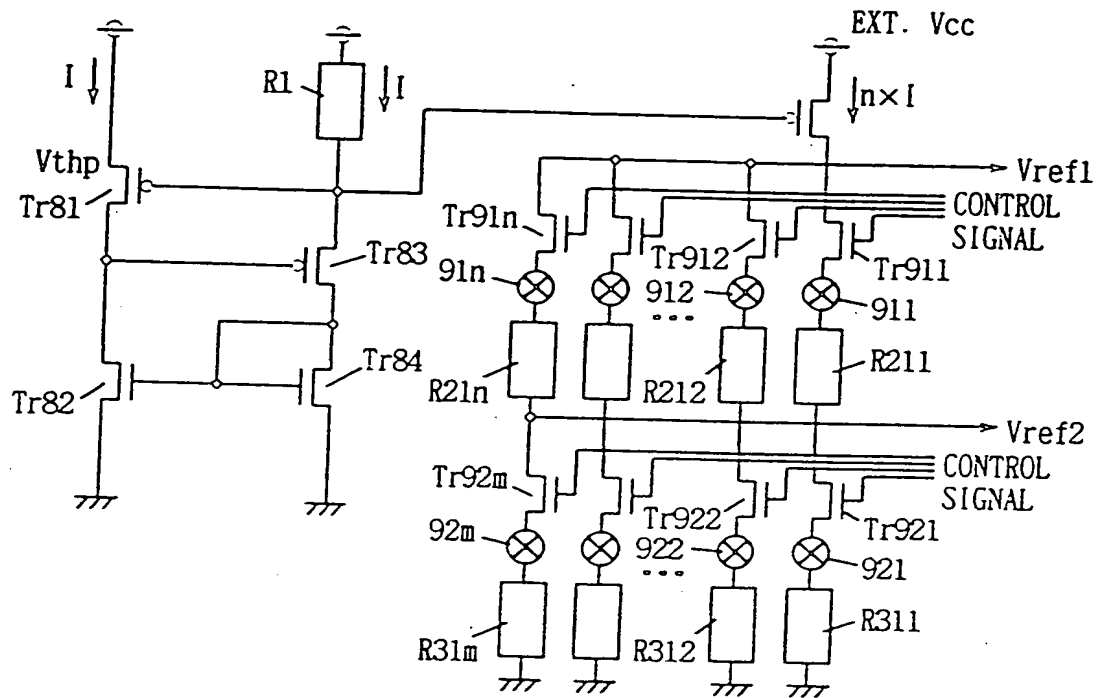
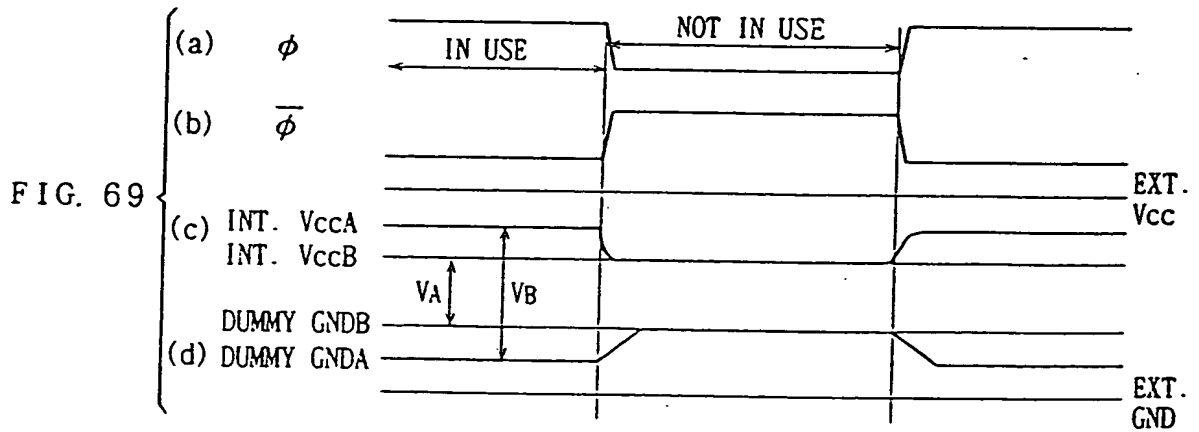
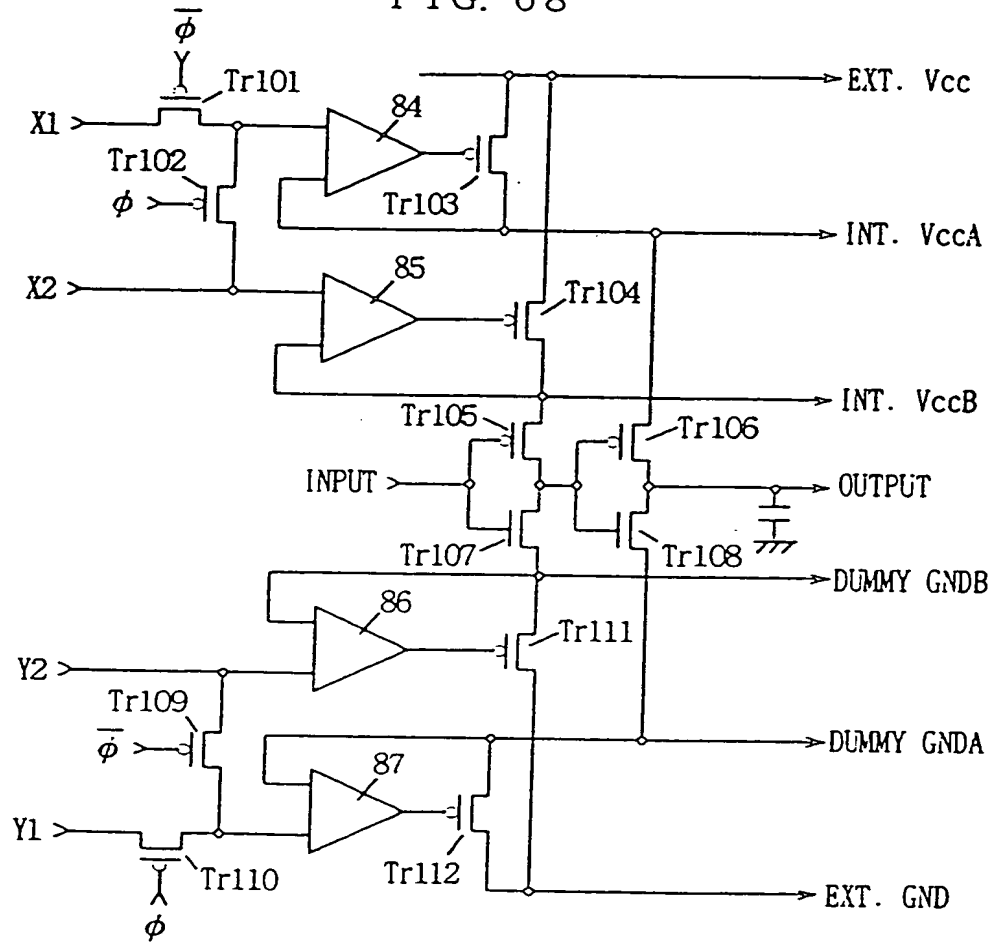


FIG. 68



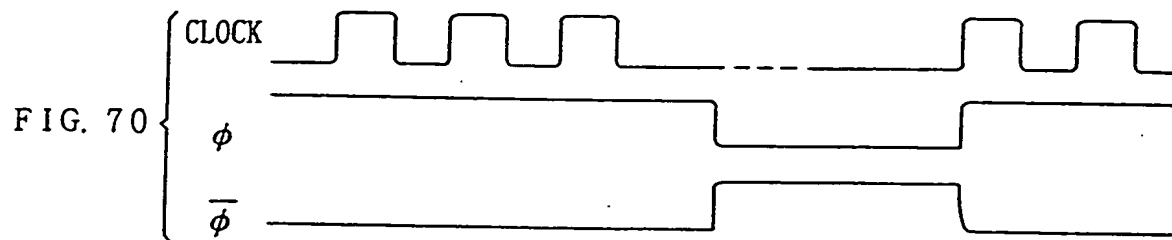


FIG. 71

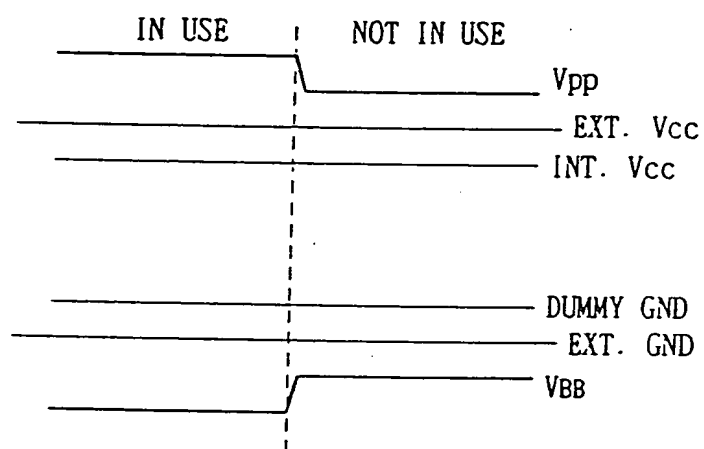


FIG. 72

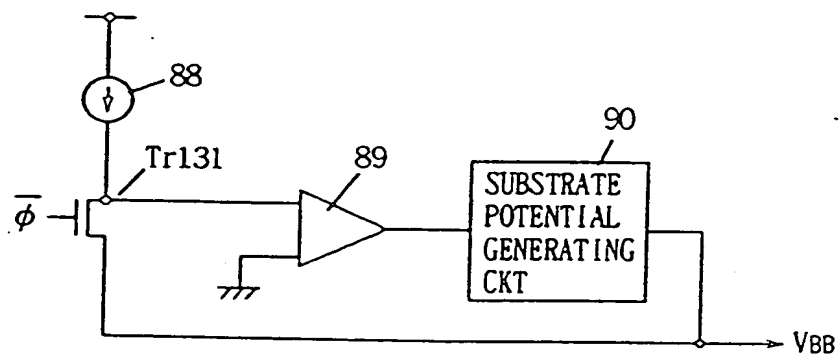


FIG. 73

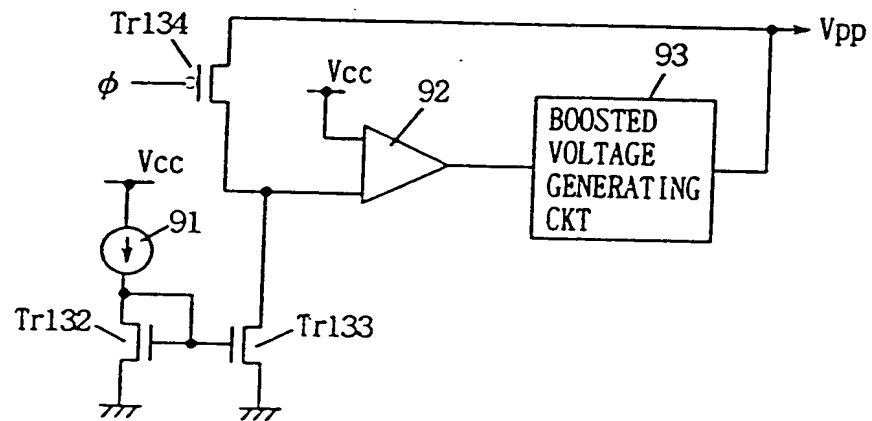


FIG. 74

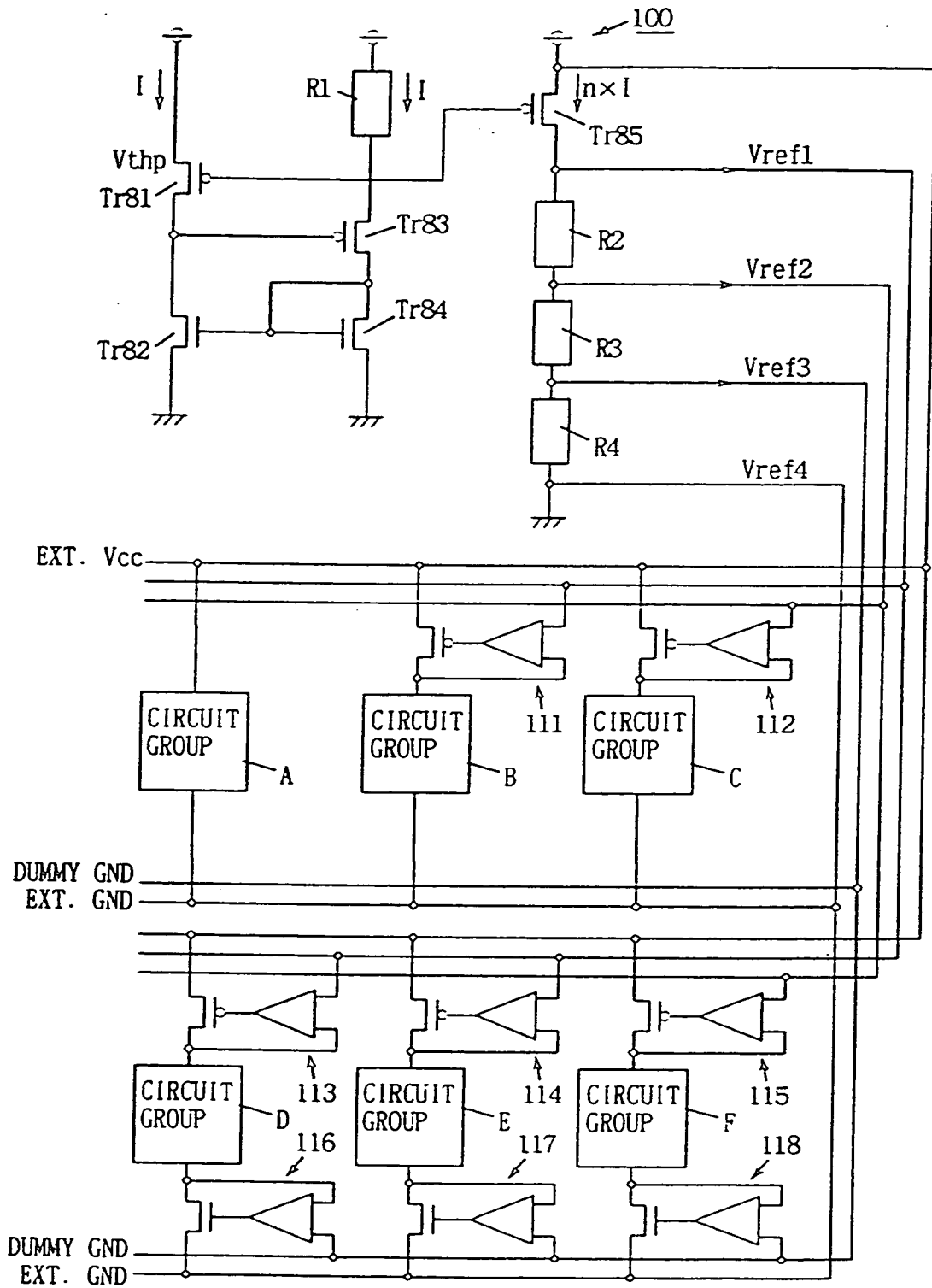


FIG. 75

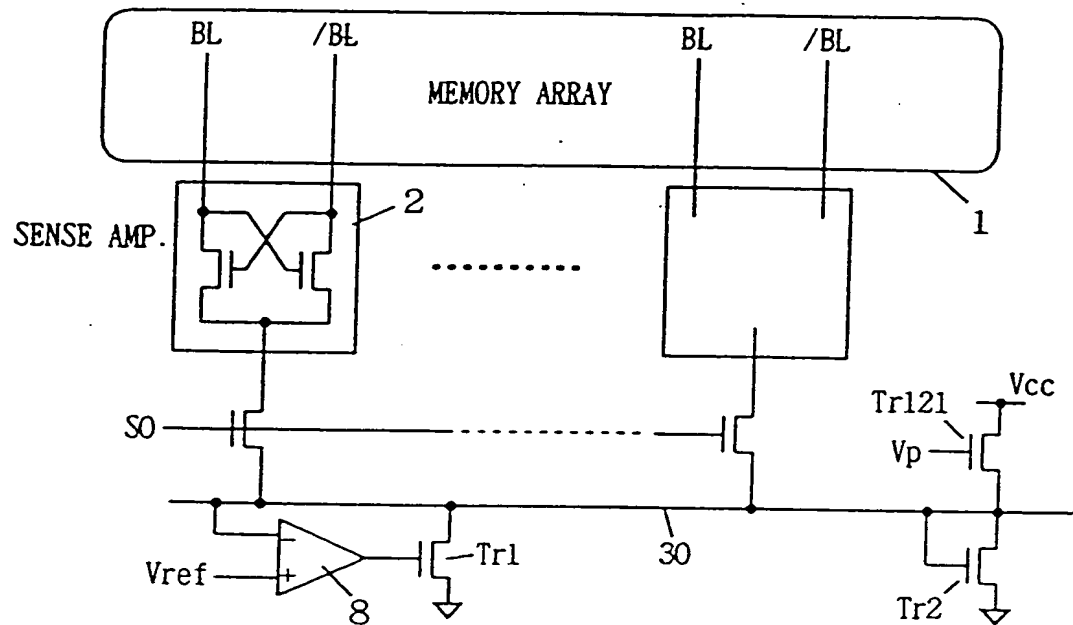


FIG. 76

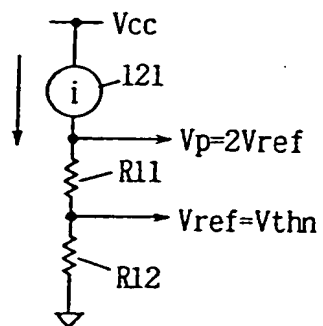


FIG. 77

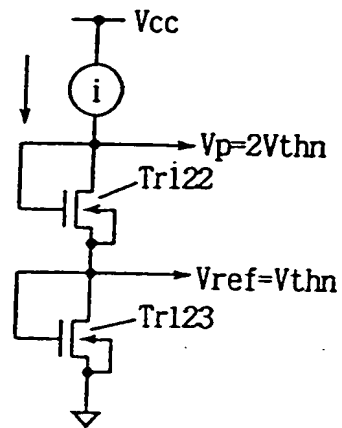


FIG. 78

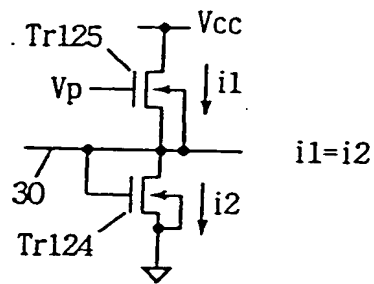


FIG. 79

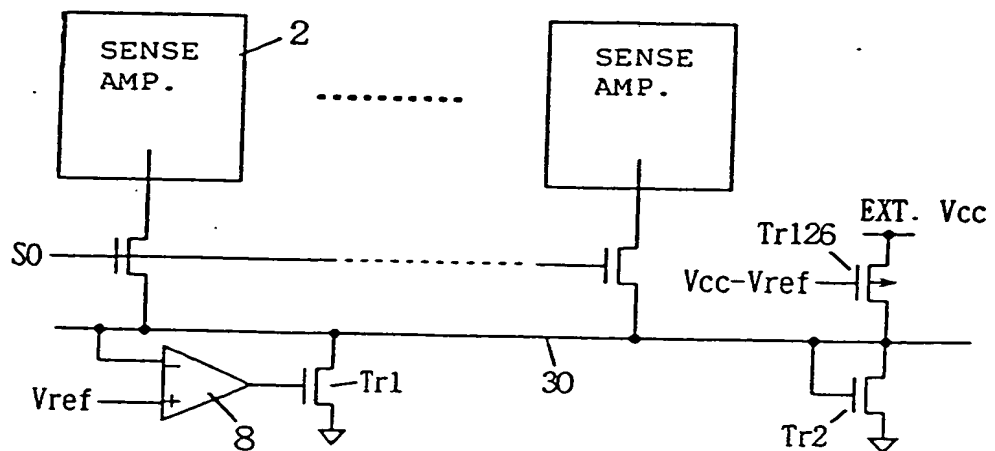


FIG. 80

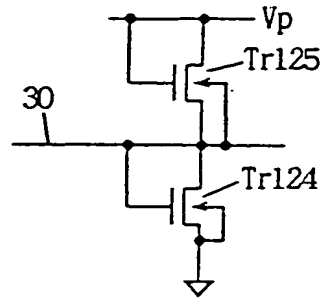


FIG. 81

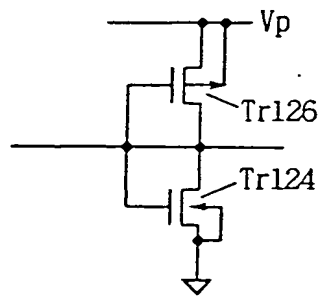
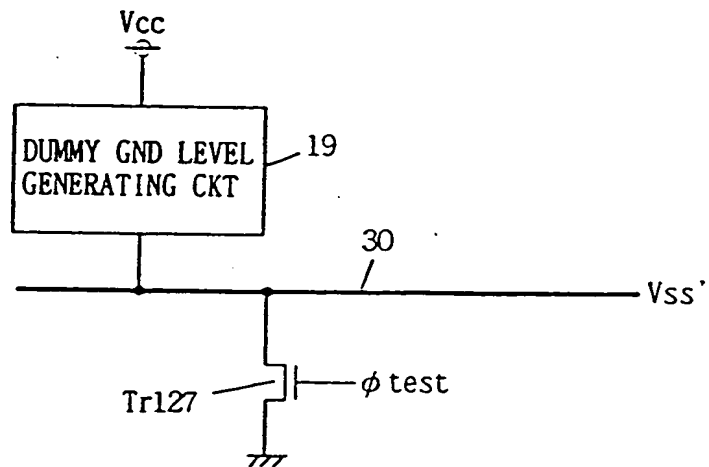


FIG. 82



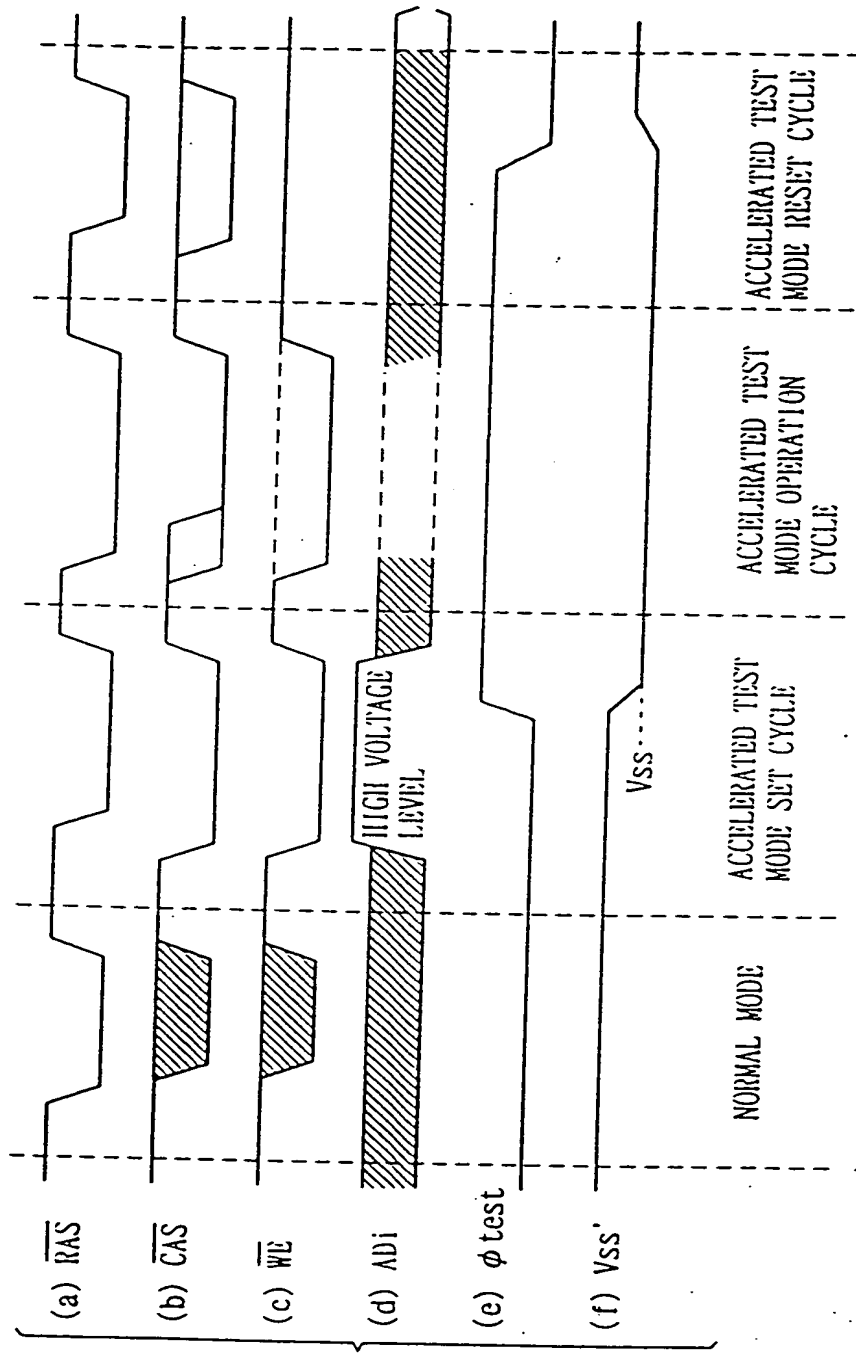


FIG. 83

FIG. 84

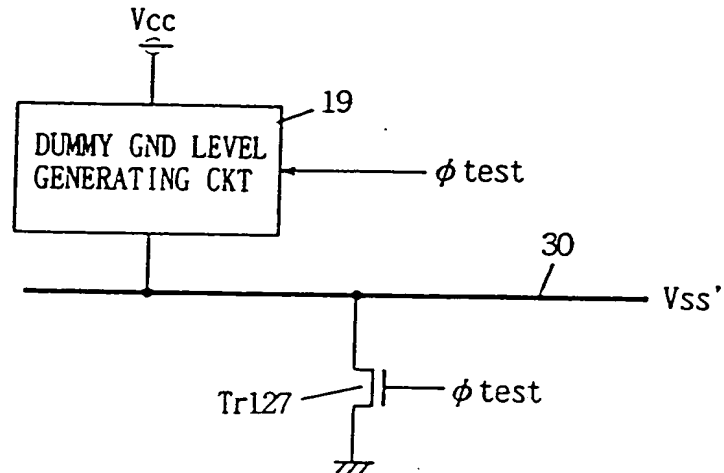


FIG. 85

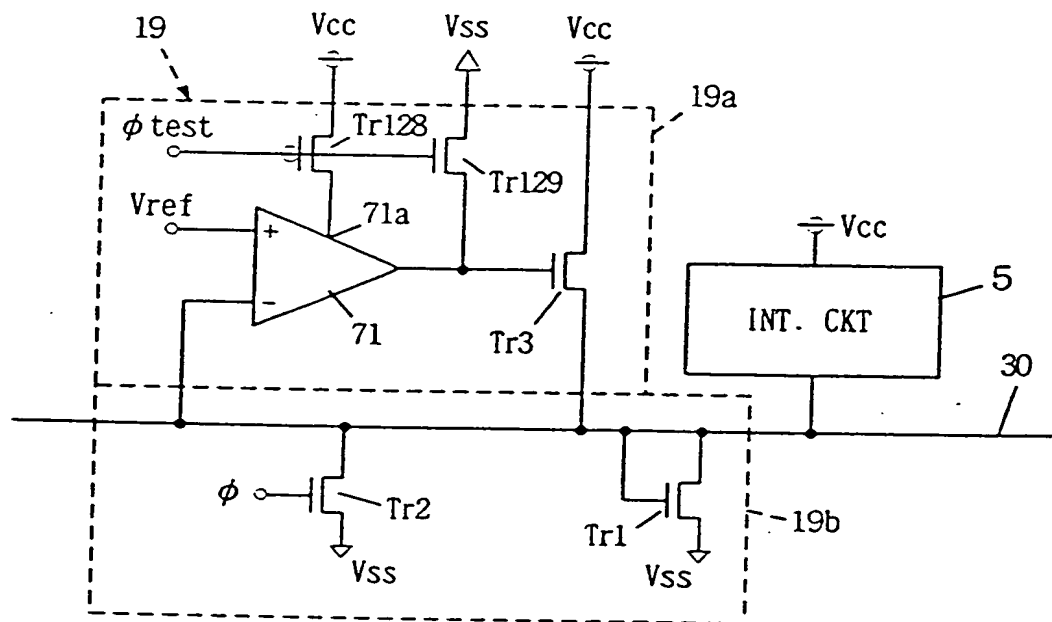


FIG. 86

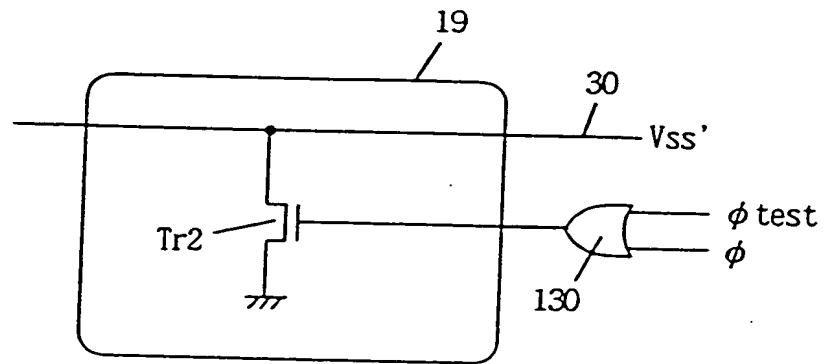
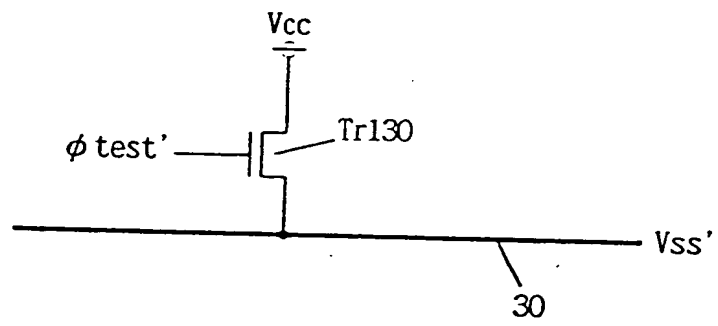


FIG. 87



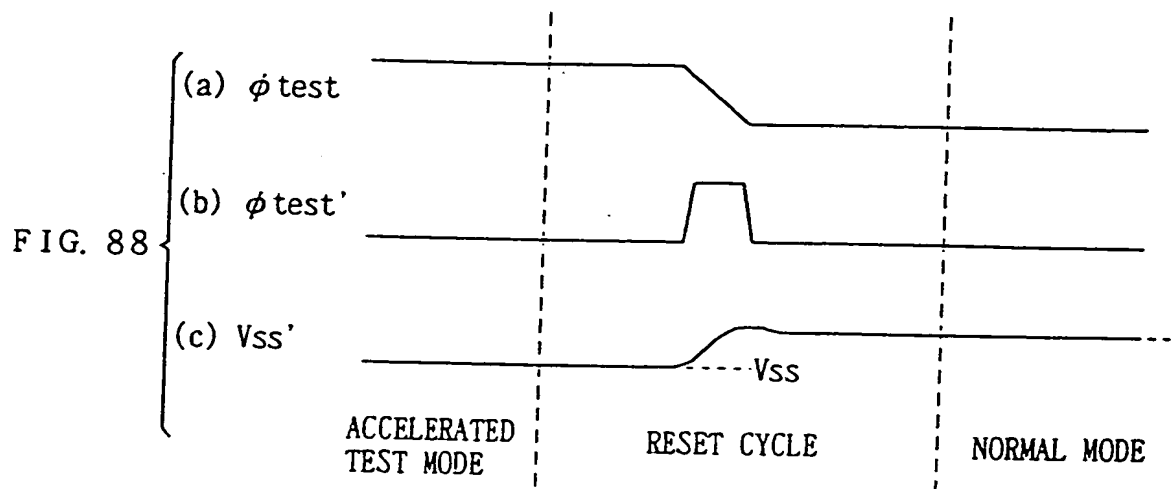


FIG. 89

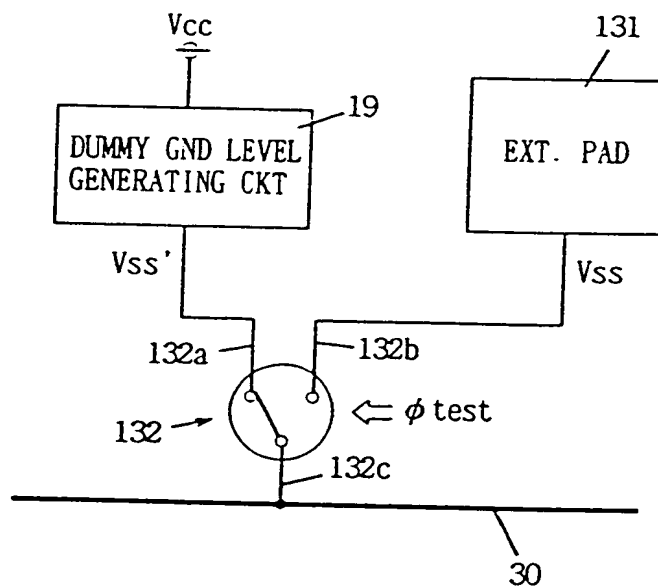


FIG. 90

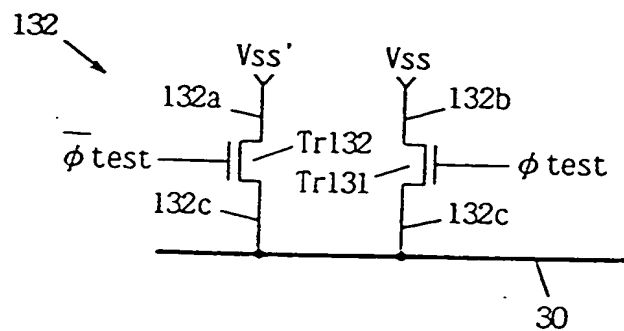


FIG. 91

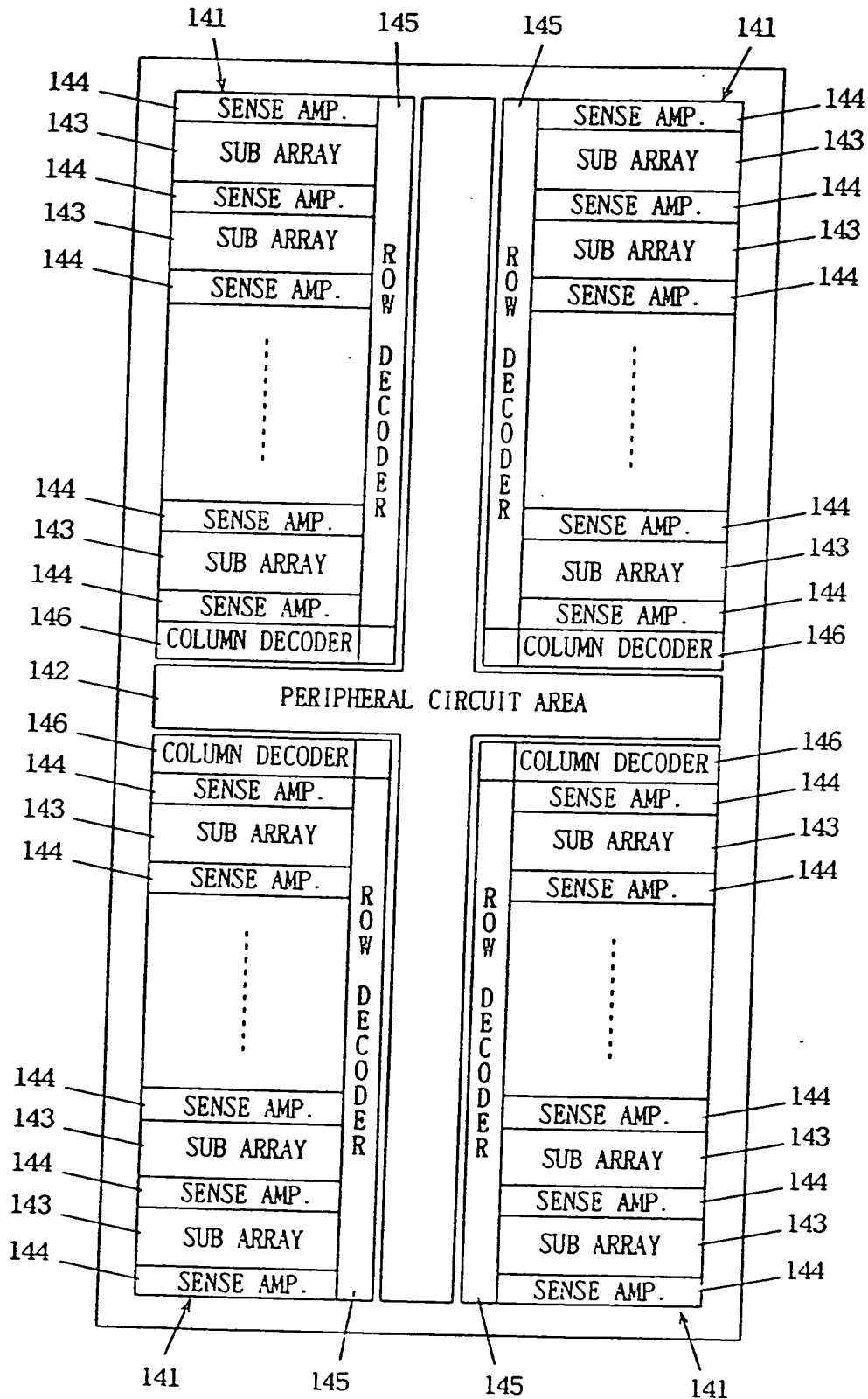


FIG. 92

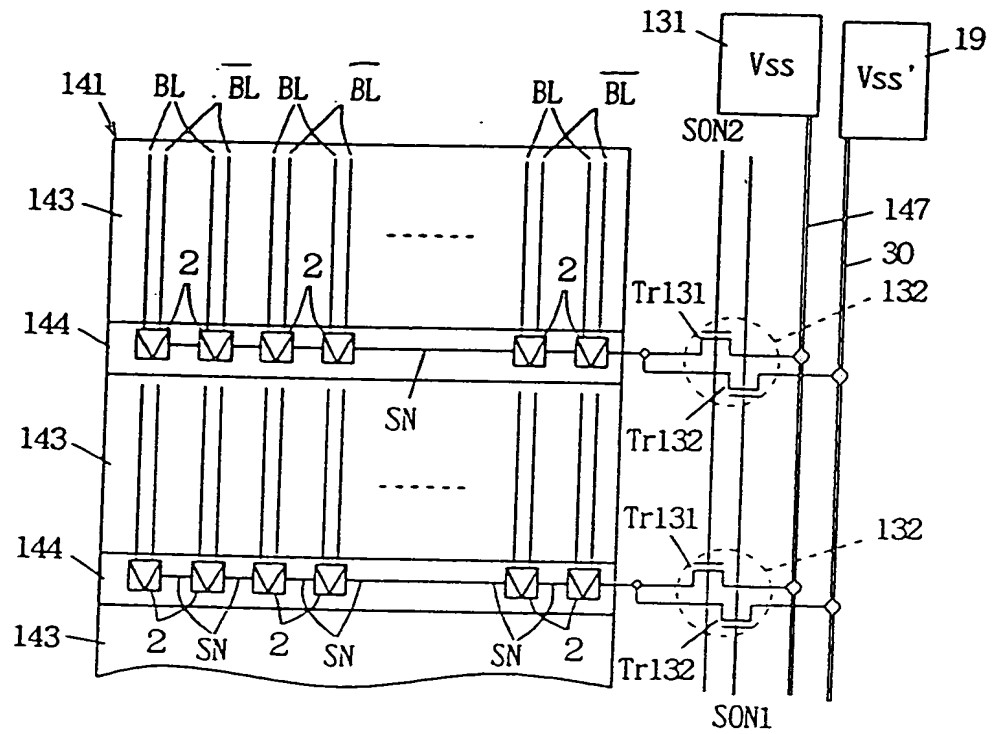


FIG. 93

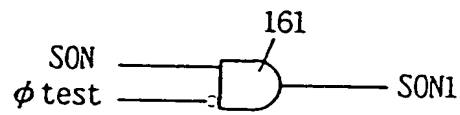


FIG. 94

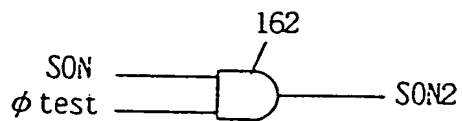


FIG. 95

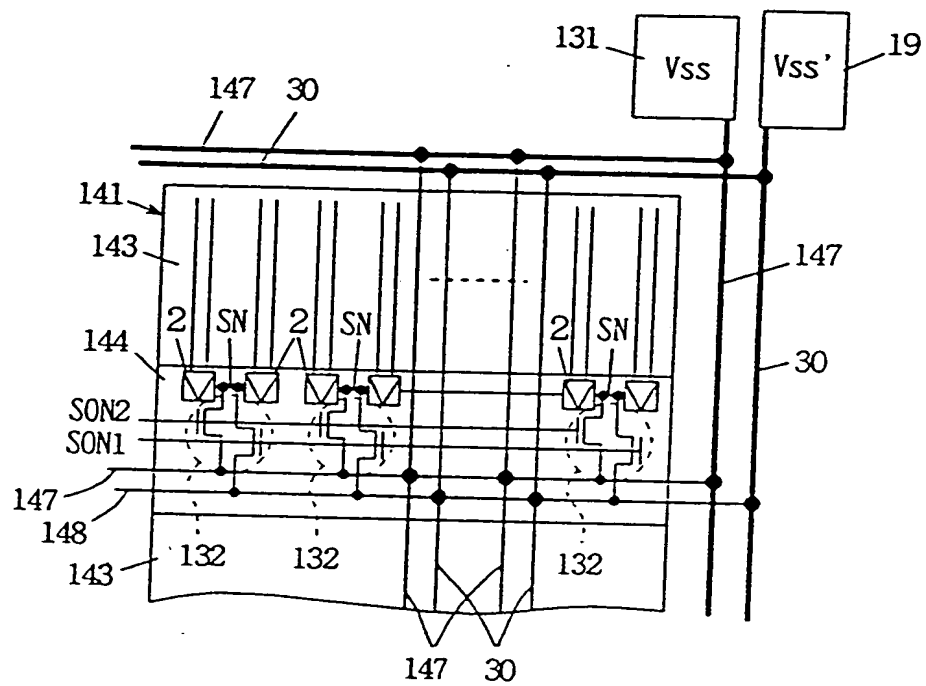


FIG. 96

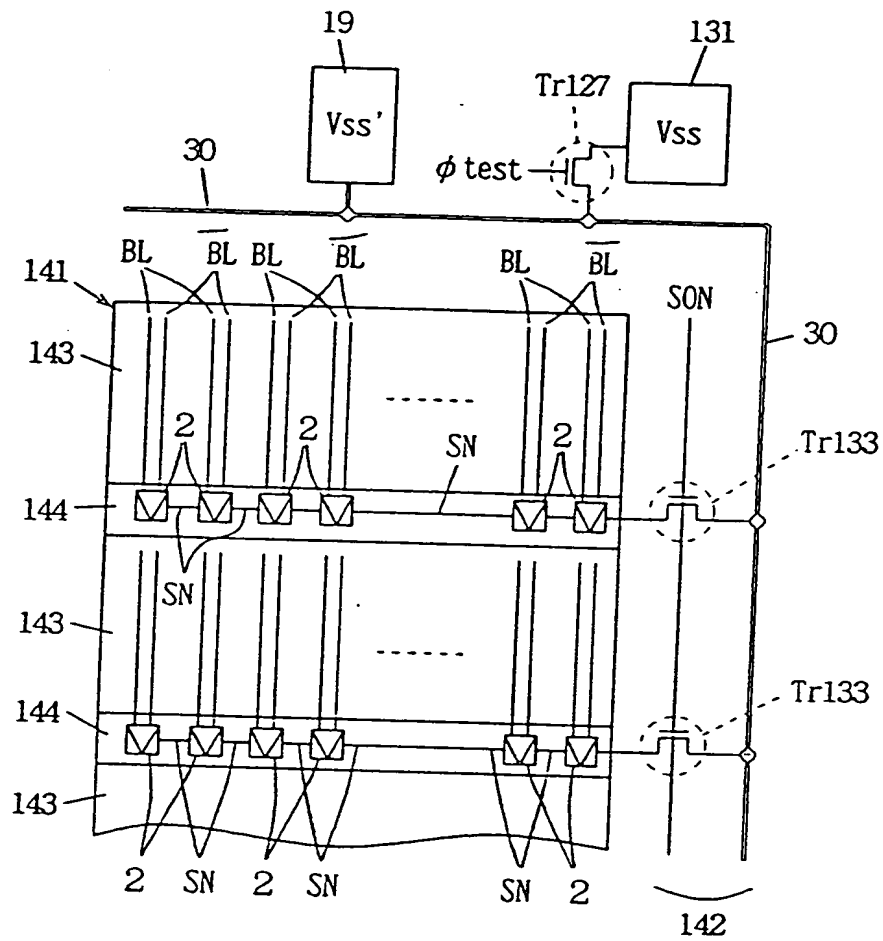


FIG. 97

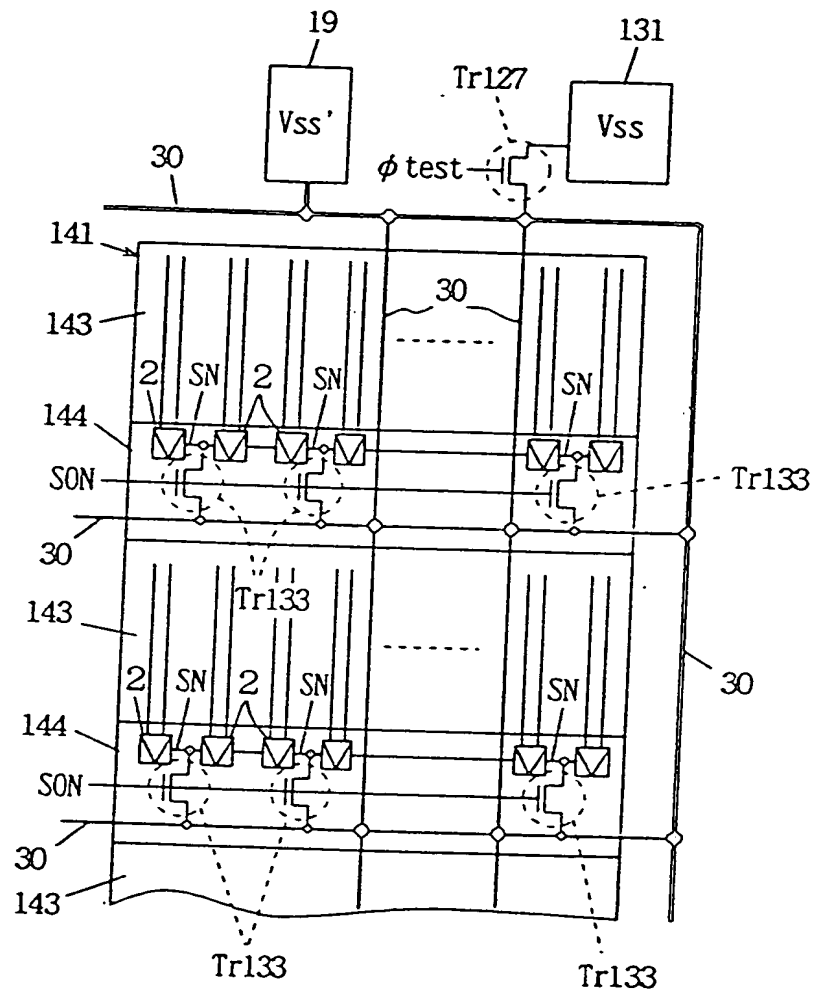
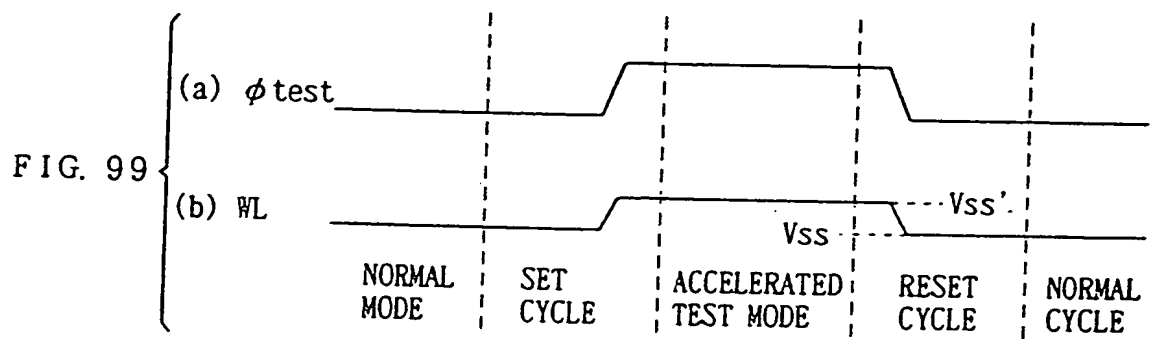
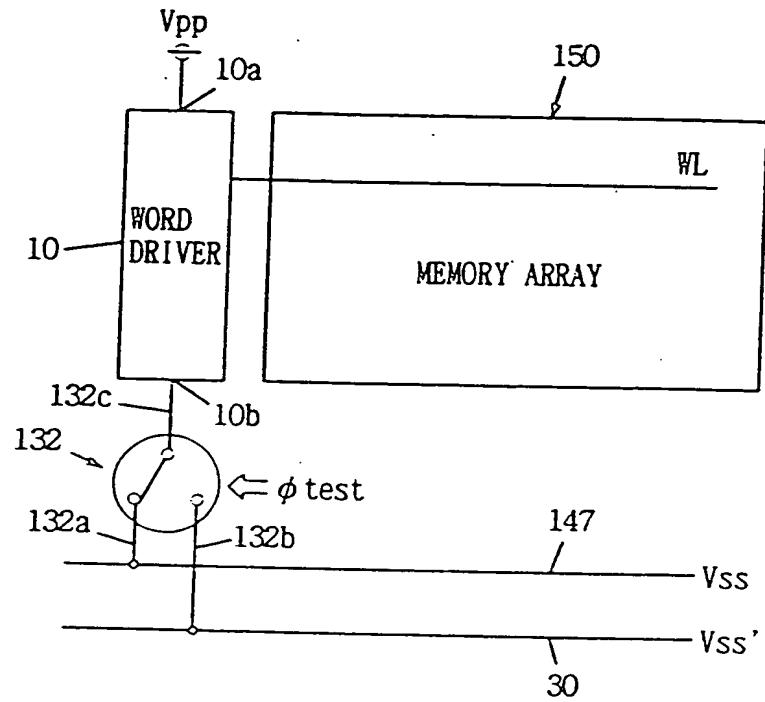


FIG. 98



The block diagram illustrates a memory device architecture. A **WORD DRIVER** (10) is connected to a **MEMORY ARRAY** (150) via a word line (**WL**). The memory array is also connected to a **BL, /BL** line. A **SENSE AMP. BAND** (144) is connected to the **BL, /BL** line. A **NEGATIVE POTENTIAL GENERATING CKT** (152) provides a **Vbb** signal (132a) to a switch (132). The switch (132) is controlled by a **φ test** signal (132b) and connects the **Vbb** signal to an **EXT. PAD** (131) via a node (132c). The **EXT. PAD** (131) is also connected to a **Vss** signal (132b).

FIG. 102
PRIOR ART

